

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				2 *****
				3 *
				4 * Zvector E7 instruction tests for VRR-c encoded:
				5 *
				6 * E768 VN - Vector AND
				7 * E769 VNC - Vector AND with Complement
				8 * E76A V0 - Vector OR
				9 * E76B VN0 - Vector NOR
				10 * E76C VNX - Vector Not Exclusive OR
				11 * E76D VX - Vector Exclusive OR
				12 * E76E VNN - Vector NAND
				13 * E76F VOC - Vector OR with Complement
				14 *
				15 * James Wekel March 2025
				16 *****
				18 *****
				19 *
				20 * basic instruction tests
				21 *
				22 *****
				23 * This program tests proper functioning of the z/arch E7 VRR-c vector
				24 * logical (and, and with complement, or, nor, not xor, xor, nand)
				25 * instructions.
				26 *
				27 * Exceptions are not tested.
				28 *
				29 * PLEASE NOTE that the tests are very SIMPLE TESTS designed to catch
				30 * obvious coding errors. None of the tests are thorough. They are
				31 * NOT designed to test all aspects of any of the instructions.
				32 *
				33 *****
				34 *
				35 * *Testcase zvector-e7-11-logical
				36 * *
				37 * * Zvector E7 instruction tests for VRR-c encoded:
				38 * *
				39 * * E768 VN - Vector AND
				40 * * E769 VNC - Vector AND with Complement
				41 * * E76A V0 - Vector OR
				42 * * E76B VN0 - Vector NOR
				43 * * E76C VNX - Vector Not Exclusive OR
				44 * * E76D VX - Vector Exclusive OR
				45 * * E76E VNN - Vector NAND
				46 * * E76F VOC - Vector OR with Complement
				47 * *
				48 * * # -----
				49 * * # This tests only the basic function of the instructions.
				50 * * # Exceptions are NOT tested.
				51 * * # -----
				52 * *
				53 * mai nsi ze 2
				54 * numcpu 1
				55 * sysclear
				56 * archlvl z/Arch

57	*			
58	*	loadcore	"\$(testpath)/zvector-e7-11-logical.core"	0x0
59	*			
60	*	diag8cmd	enable	# (needed for messages to Hercules console)
61	*	runtest	2	
62	*	diag8cmd	disable	# (reset back to default)
63	*			
64	*	*Done		
65	*			
66	*	*****		

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
68				*****
69	*			FCHECK Macro - Is a Facility Bit set?
70	*			
71	*			If the facility bit is NOT set, an message is issued and
72	*			the test is skipped.
73	*			
74	*			Fcheck uses R0, R1 and R2
75	*			
76	* eg.			FCHECK 134, 'vector-packed-decimal'
77	*****			*****
78				MACRO
79				FCHECK &BITNO, &NOTSETMSG
80	. *			&BITNO : facility bit number to check
81	. *			&NOTSETMSG : 'facility name'
82		LCLA	&FBBYTE	Facility bit in Byte
83		LCLA	&FBBIT	Facility bit within Byte
84				
85		LCLA	&L(8)	
86	&L(1)	SetA	128, 64, 32, 16, 8, 4, 2, 1	bit positions within byte
87				
88	&FBBYTE	SETA	&BITNO/8	
89	&FBBIT	SETA	&L((&BITNO-(&FBBYTE*8))+1)	
90	. *	MNOTE	0, 'checking Bit=&BITNO: FBBYTE=&FBBYTE, FBBIT=&FBBIT'	
91				
92		B	X&SYSNDX	
93	*			Fcheck data area
94	*			skip messgae
95	SKT&SYSNDX DC	C'	Skipping tests: '	
96		DC	C&NOTSETMSG	
97		DC	C' (bit &BITNO) is not installed.'	
98	SKL&SYSNDX EQU	*	- SKT&SYSNDX	
99	*			facility bits
100		DS	FD	gap
101	FB&SYSNDX DS		4FD	
102		DS	FD	gap
103	*			
104	X&SYSNDX EQU *			
105		LA	R0, ((X&SYSNDX- FB&SYSNDX)/8)-1	
106		STFLE	FB&SYSNDX	get facility bits
107				
108		XGR	R0, R0	
109		IC	R0, FB&SYSNDX+&FBBYTE	get fbit byte
110		N	R0, =F' &FBBIT'	is bit set?
111		BNZ	XC&SYSNDX	
112	*			
113	*			facility bit not set, issue message and exit
114	*			
115		LA	R0, SKL&SYSNDX	message length
116		LA	R1, SKT&SYSNDX	message address
117		BAL	R2, MSG	
118				
119		B	EOJ	
120	XC&SYSNDX EQU *			
121				MEND

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
				123	*****		
				124	* Low core PSWs		
				125	*****		
00000000		00000000	0000291F	126	ZVE7TST START 0		
		00000000		127	USING ZVE7TST, R0	Low core addressability	
				128			
		00000140	00000000	129	SVOLDPSW EQU ZVE7TST+X' 140'	z/Arch Supervisor call old PSW	
00000000		00000000	000001A0	131	ORG ZVE7TST+X' 1A0'	z/Architecture RESTART PSW	
000001A0	00000001 80000000			132	DC X' 0000000180000000'		
000001A8	00000000 00000200			133	DC AD(BEGIN)		
000001B0		000001B0	000001D0	135	ORG ZVE7TST+X' 1D0'	z/Architecture PROGRAM CHECK PSW	
000001D0	00020001 80000000			136	DC X' 0002000180000000'		
000001D8	00000000 0000DEAD			137	DC AD(X' DEAD')		
000001E0		000001E0	00000200	139	ORG ZVE7TST+X' 200'	Start of actual test program..	
				141	*****		
				142	* The actual "ZVE7TST" program itself...		
				143	*****		
				144	* Architecture Mode: z/Arch		
				145	* Register Usage:		
				146	* R0 (work)		
				147	* R1-4 (work)		
				148	* R5 Testing control table - current test base		
				149	* R6- R7 (work)		
				150	* R8 First base register		
				151	* R9 Second base register		
				152	* R10 Third base register		
				153	* R11 E7TEST call return		
				154	* R12 E7TESTS register		
				155	* R13 (work)		
				156	* R14 Subroutine call		
				157	* R15 Secondary Subroutine call or work		
				158	* R15 Secondary Subroutine call or work		
				159	* R15 Secondary Subroutine call or work		
				160	* R15 Secondary Subroutine call or work		
				161	*****		
00000200		00000200		163	USING BEGIN, R8	FIRST Base Register	
00000200		00001200		164	USING BEGIN+4096, R9	SECOND Base Register	
00000200		00002200		165	USING BEGIN+8192, R10	THIRD Base Register	
00000200	0580			167	BEGIN BALR R8, 0	Inititalize FIRST base register	
00000202	0680			168	BCTR R8, 0	Inititalize FIRST base register	
00000204	0680			169	BCTR R8, 0	Inititalize FIRST base register	
00000206	4190 8800		00000800	171	LA R9, 2048(, R8)	Inititalize SECOND base register	
0000020A	4190 9800		00000800	172	LA R9, 2048(, R9)	Inititalize SECOND base register	
				173			

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
0000020E	41A0 9800		00000800	174	LA	R10, 2048(, R9)	Initialize THIRD base register
00000212	41A0 A800		00000800	175	LA	R10, 2048(, R10)	Initialize THIRD base register
				176			
00000216	B600 8324		00000524	177	STCTL	R0, R0, CTLR0	Store CR0 to enable AFP
0000021A	9604 8325		00000525	178	OI	CTLR0+1, X' 04'	Turn on AFP bit
0000021E	9602 8325		00000525	179	OI	CTLR0+1, X' 02'	Turn on Vector bit
00000222	B700 8324		00000524	180	LCTL	R0, R0, CTLR0	Reload updated CR0
				181			
				182	*****		
				183	* Is z/Architecture vector facility installed (bit 129)		
				184	*****		
				185			
00000226	47F0 80A8		000002A8	186	FCHECK	129, 'z/Architecture vector facility'	
				187+	B	X0001	
				188+*			Fcheck data area
				189+*			skip messgae
0000022A	40404040 E2928997			190+SKT0001	DC	C'	Skipping tests: '
0000023E	A961C199 838889A3			191+	DC	C' z/Architecture vector facility'	
0000025C	404D8289 A340F1F2			192+	DC	C' (bit 129) is not installed.'	
		0000004E	00000001	193+SKL0001	EQU	*- SKT0001	
				194+*			facility bits
00000278	00000000 00000000			195+	DS	FD	gap
00000280	00000000 00000000			196+FB0001	DS	4FD	
000002A0	00000000 00000000			197+	DS	FD	gap
				198+*			
		000002A8	00000001	199+X0001	EQU	*	
000002A8	4100 0004		00000004	200+	LA	R0, ((X0001- FB0001)/8)-1	
000002AC	B2B0 8080		00000280	201+	STFLE	FB0001	get facility bits
000002B0	B982 0000			202+	XGR	R0, R0	
000002B4	4300 8090		00000290	203+	IC	R0, FB0001+16	get fbit byte
000002B8	5400 832C		0000052C	204+	N	R0, =F' 64'	is bit set?
000002BC	4770 80D0		000002D0	205+	BNZ	XC0001	
				206+*			
				207+*	facility bit not set, issue message and exit		
				208+*			
000002C0	4100 004E		0000004E	209+	LA	R0, SKL0001	message length
000002C4	4110 802A		0000022A	210+	LA	R1, SKT0001	message address
000002C8	4520 8240		00000440	211+	BAL	R2, MSG	
000002CC	47F0 8308		00000508	212+	B	EOJ	
		000002D0	00000001	213+XC0001	EQU	*	
				214			
				215	*****		
				216	* Is z/Architecture vector enhancements facility 1 installed (bit 135)		
				217	* required by:		
				218	* E76C VNX - Vector Not Exclusive OR		
				219	* E76E VNN - Vector NAND		
				220	*****		
				221			
000002D0	47F0 8158		00000358	222	FCHECK	135, 'z/Arch vector enhance facility 1'	
				223+	B	X0002	
				224+*			Fcheck data area
				225+*			skip messgae
000002D4	40404040 E2928997			226+SKT0002	DC	C'	Skipping tests: '
000002E8	A961C199 838840A5			227+	DC	C' z/Arch vector enhance facility 1'	
00000308	404D8289 A340F1F3			228+	DC	C' (bit 135) is not installed.'	
		00000050	00000001	229+SKL0002	EQU	*- SKT0002	

[illegible]

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				376 *****
				377 * Normal completion or Abnormal termination PSWs
				378 *****
000004F8	00020001 80000000			380 EOJPSW DC 0D' 0' , X' 0002000180000000' , AD(0)
00000508	B2B2 82F8		000004F8	382 EOJ LPSWE EOJPSW Normal completion
00000510	00020001 80000000			384 FAILPSW DC 0D' 0' , X' 0002000180000000' , AD(X' BAD')
00000520	B2B2 8310		00000510	386 FAILTEST LPSWE FAILPSW Abnormal termination
				388 *****
				389 * Working Storage
				390 *****
00000524	00000000			392 CTLR0 DS F CRO
00000528	00000000			393 DS F
0000052C				395 LTORG , Literals pool
0000052C	00000040			396 =F' 64'
00000530	00000001			397 =F' 1'
00000534	00002870			398 =A(E7TESTS)
00000538	0000			399 =H' 0'
0000053A	005F			400 =AL2(L' MSGMSG)
				401
				402 * some constants
				403
	00000400	00000001		404 K EQU 1024 One KB
	00001000	00000001		405 PAGE EQU (4*K) Size of one page
	00010000	00000001		406 K64 EQU (64*K) 64 KB
	00100000	00000001		407 MB EQU (K*K) 1 MB
				408
	AABBCCDD	00000001		409 REG2PATT EQU X' AABBCCDD' Polluted Register pattern
	000000DD	00000001		410 REG2LOW EQU X' DD' (last byte above)

LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				450	*****
				451	* E7TEST DSECT
				452	*****
				454	E7TEST DSECT ,
00000000	00000000			455	TSUB DC A(0) pointer to test
00000004	0000			456	TNUM DC H' 00' Test Number
00000006	00			457	DC X' 00'
00000007	00			458	DC HL1' 00' m field - not used
				459	
00000008	40404040	40404040		460	OPNAME DC CL8' ' E7 name
00000010	00000000			461	V2ADDR DC A(0) address of v2 source
00000014	00000000			462	V3ADDR DC A(0) address of v3 source
00000018	00000000			463	RELEN DC A(0) RESULT LENGTH
0000001C	00000000			464	READDR DC A(0) result (expected) address
00000020	00000000	00000000		465	DS FD gap
00000028	00000000	00000000		466	V10OUTPUT DS XL16 V1 Output
00000038	00000000	00000000		467	DS FD gap
				468	
				469	* test routine will be here (from VRR-c macro)
				470	*
				471	* followed by
				472	* EXPECTED RESULT
000010A8		00000000	0000291F	474	ZVE7TST CSECT ,
				475	DS 0F
				477	*****
				478	* Macros to help build test tables
				479	*****
				481	*
				482	* macro to generate individual test
				483	*
				484	MACRO
				485	VRR_C &INST
				486	. * &INST - VRR-c instruction under test
				487	. * no m fields
				488	
				489	GBLA &TNUM
				490	&TNUM SETA &TNUM+1
				491	
				492	DS 0FD
				493	USING *, R5 base for test data and test routine
				494	
				495	T&TNUM DC A(X&TNUM) address of test routine
				496	DC H' &TNUM test number
				497	DC X' 00'
				498	DC HL1' 00' m field
				499	DC CL8' &INST' instruction name
				500	DC A(RE&TNUM+16) address of v2 source

LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				549	*****
				550	* E7 VRR-c tests
				551	*****
				552	PRINT DATA
				553	
				554	* E768 VN - Vector AND
				555	* E769 VNC - Vector AND with Complement
				556	* E76A V0 - Vector OR
				557	* E76B VN0 - Vector NOR
				558	* E76C VNX - Vector Not Exclusive OR
				559	* E76D VX - Vector Exclusive OR
				560	* E76E VNN - Vector NAND
				561	* E76F V0C - Vector OR with Complement
				562	
				563	* VRR-c instruction
				564	* followed by
				565	* 16 byte expected result (V1)
				566	* 16 byte V2 source
				567	* 16 byte V3 source
				568	*-----
				569	* VN - Vector AND
				570	*-----
				571	
000010A8				572	VRR_C VN
000010A8				573+	DS OFD
000010A8	000010E8	000010A8		574+	USING *, R5
000010AC	0001			575+T1	DC A(X1)
000010AE	00			576+	DC H' 1'
000010AF	00			577+	DC X' 00'
000010B0	E5D54040	40404040		578+	DC HL1' 00'
000010B8	00001120			579+	DC CL8' VN'
000010BC	00001130			580+	DC A(RE1+16)
000010C0	00000010			581+	DC A(RE1+32)
000010C4	00001110			582+	DC A(16)
000010C8	00000000	00000000		583+REA1	DC A(RE1)
000010D0	00000000	00000000		584+	DS FD
000010D8	00000000	00000000		585+V101	DS XL16
000010E0	00000000	00000000		586+	DS FD
				587+*	gap
000010E8				588+X1	DS 0F
000010E8	E310 5010 0014		00000010	589+	LGF R1, V2ADDR
000010EE	E761 0000 0806		00000000	590+	VL v22, 0(R1)
000010F4	E310 5014 0014		00000014	591+	LGF R1, V3ADDR
000010FA	E771 0000 0806		00000000	592+	VL v23, 0(R1)
00001100	E766 7000 0E68			593+	VN V22, V22, V23
00001106	E760 5028 080E		000010D0	594+	VST V22, V101
0000110C	07FB			595+	BR R11
00001110				596+RE1	DC 0F
00001110				597+	DROP R5
00001110	00000000	00000000		598	DC XL16' 0000000000000000 0000000000000000'
00001118	00000000	00000000			result t
00001120	00000000	00000000		599	DC XL16' 0000000000000000 0000000000000000'
00001128	00000000	00000000			v2
00001130	00000000	00000000		600	DC XL16' 0000000000000000 0000000000000000'
00001138	00000000	00000000			v3

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
				601		
				602	VRR_C VN	
00001140				603+	DS OFD	
00001140		00001140		604+	USING *, R5	base for test data and test routine
00001140	00001180			605+T2	DC A(X2)	address of test routine
00001144	0002			606+	DC H' 2'	test number
00001146	00			607+	DC X' 00'	
00001147	00			608+	DC HL1' 00'	m field
00001148	E5D54040 40404040			609+	DC CL8' VN'	instruction name
00001150	000011B8			610+	DC A(RE2+16)	address of v2 source
00001154	000011C8			611+	DC A(RE2+32)	address of v3 source
00001158	00000010			612+	DC A(16)	result length
0000115C	000011A8			613+REA2	DC A(RE2)	result address
00001160	00000000 00000000			614+	DS FD	gap
00001168	00000000 00000000			615+V102	DS XL16	V1 output
00001170	00000000 00000000					
00001178	00000000 00000000			616+	DS FD	gap
				617+*		
00001180				618+X2	DS OF	
00001180	E310 5010 0014		00000010	619+	LGF R1, V2ADDR	load v2 source
00001186	E761 0000 0806		00000000	620+	VL v22, 0(R1)	use v22 to test decoder
0000118C	E310 5014 0014		00000014	621+	LGF R1, V3ADDR	load v3 source
00001192	E771 0000 0806		00000000	622+	VL v23, 0(R1)	use v23 to test decoder
00001198	E766 7000 0E68			623+	VN V22, V22, V23	test instruction (dest is a source)
0000119E	E760 5028 080E		00001168	624+	VST V22, V102	save v1 output
000011A4	07FB			625+	BR R11	return
000011A8				626+RE2	DC OF	xl16 expected result
000011A8				627+	DROP R5	
000011A8	FFFFFFFF FFFFFFFF			628	DC XL16' FFFFFFFFFFFFFFFFFF FFFFFFFFFFFFFFFFFF'	result t
000011B0	FFFFFFFF FFFFFFFF					
000011B8	FFFFFFFF FFFFFFFF			629	DC XL16' FFFFFFFFFFFFFFFFFF FFFFFFFFFFFFFFFFFF'	v2
000011C0	FFFFFFFF FFFFFFFF					
000011C8	FFFFFFFF FFFFFFFF			630	DC XL16' FFFFFFFFFFFFFFFFFF FFFFFFFFFFFFFFFFFF'	v3
000011D0	FFFFFFFF FFFFFFFF					
				631		
				632	VRR_C VN	
000011D8				633+	DS OFD	
000011D8		000011D8		634+	USING *, R5	base for test data and test routine
000011D8	00001218			635+T3	DC A(X3)	address of test routine
000011DC	0003			636+	DC H' 3'	test number
000011DE	00			637+	DC X' 00'	
000011DF	00			638+	DC HL1' 00'	m field
000011E0	E5D54040 40404040			639+	DC CL8' VN'	instruction name
000011E8	00001250			640+	DC A(RE3+16)	address of v2 source
000011EC	00001260			641+	DC A(RE3+32)	address of v3 source
000011F0	00000010			642+	DC A(16)	result length
000011F4	00001240			643+REA3	DC A(RE3)	result address
000011F8	00000000 00000000			644+	DS FD	gap
00001200	00000000 00000000			645+V103	DS XL16	V1 output
00001208	00000000 00000000					
00001210	00000000 00000000			646+	DS FD	gap
				647+*		
00001218				648+X3	DS OF	
00001218	E310 5010 0014		00000010	649+	LGF R1, V2ADDR	load v2 source
0000121E	E761 0000 0806		00000000	650+	VL v22, 0(R1)	use v22 to test decoder
00001224	E310 5014 0014		00000014	651+	LGF R1, V3ADDR	load v3 source

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
0000122A	E771 0000 0806		00000000	652+	VL	v23, 0(R1)	use v23 to test decoder
00001230	E766 7000 0E68			653+	VN	V22, V22, V23	test instruction (dest is a source)
00001236	E760 9000 080E		00001200	654+	VST	V22, V103	save v1 output
0000123C	07FB			655+	BR	R11	return
00001240				656+RE3	DC	0F	xl16 expected result
00001240				657+	DROP	R5	
00001240	00010203 04050607			658	DC	XL16' 0001020304050607 08090A0B0C0D0E0F'	result t
00001248	08090A0B 0C0D0E0F						
00001250	00010203 04050607			659	DC	XL16' 0001020304050607 08090A0B0C0D0E0F'	v2
00001258	08090A0B 0C0D0E0F						
00001260	FFFFFFFF FFFFFFFF			660	DC	XL16' FFFFFFFFFFFFFFFFFF FFFFFFFFFFFFFFFFFF'	v3
00001268	FFFFFFFF FFFFFFFF						
				661			
				662	VRR_C	VN	
00001270				663+	DS	0FD	
00001270		00001270		664+	USING	*, R5	base for test data and test routine
00001270	000012B0			665+T4	DC	A(X4)	address of test routine
00001274	0004			666+	DC	H' 4'	test number
00001276	00			667+	DC	X' 00'	
00001277	00			668+	DC	HL1' 00'	m field
00001278	E5D54040 40404040			669+	DC	CL8' VN'	instruction name
00001280	000012E8			670+	DC	A(RE4+16)	address of v2 source
00001284	000012F8			671+	DC	A(RE4+32)	address of v3 source
00001288	00000010			672+	DC	A(16)	result length
0000128C	000012D8			673+REA4	DC	A(RE4)	result address
00001290	00000000 00000000			674+	DS	FD	gap
00001298	00000000 00000000			675+V104	DS	XL16	V1 output
000012A0	00000000 00000000						
000012A8	00000000 00000000			676+	DS	FD	gap
				677+*			
000012B0				678+X4	DS	0F	
000012B0	E310 5010 0014		00000010	679+	LGF	R1, V2ADDR	load v2 source
000012B6	E761 0000 0806		00000000	680+	VL	v22, 0(R1)	use v22 to test decoder
000012BC	E310 5014 0014		00000014	681+	LGF	R1, V3ADDR	load v3 source
000012C2	E771 0000 0806		00000000	682+	VL	v23, 0(R1)	use v23 to test decoder
000012C8	E766 7000 0E68			683+	VN	V22, V22, V23	test instruction (dest is a source)
000012CE	E760 5028 080E		00001298	684+	VST	V22, V104	save v1 output
000012D4	07FB			685+	BR	R11	return
000012D8				686+RE4	DC	0F	xl16 expected result
000012D8				687+	DROP	R5	
000012D8	F0E0D0C0 B0A09080			688	DC	XL16' F0E0D0C0B0A09080 7060504030201000'	result t
000012E0	70605040 30201000						
000012E8	FFFFFFFF FFFFFFFF			689	DC	XL16' FFFFFFFFFFFFFFFFFF FFFFFFFFFFFFFFFFFF'	v2
000012F0	FFFFFFFF FFFFFFFF						
000012F8	F0E0D0C0 B0A09080			690	DC	XL16' F0E0D0C0B0A09080 7060504030201000'	v3
00001300	70605040 30201000						
				691			
				692	VRR_C	VN	
00001308				693+	DS	0FD	
00001308		00001308		694+	USING	*, R5	base for test data and test routine
00001308	00001348			695+T5	DC	A(X5)	address of test routine
0000130C	0005			696+	DC	H' 5'	test number
0000130E	00			697+	DC	X' 00'	
0000130F	00			698+	DC	HL1' 00'	m field
00001310	E5D54040 40404040			699+	DC	CL8' VN'	instruction name
00001318	00001380			700+	DC	A(RE5+16)	address of v2 source

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
0000131C	00001390			701+	DC	A(RE5+32)	address of v3 source
00001320	00000010			702+	DC	A(16)	result length
00001324	00001370			703+REA5	DC	A(RE5)	result address
00001328	00000000 00000000			704+	DS	FD	gap
00001330	00000000 00000000			705+V105	DS	XL16	V1 output
00001338	00000000 00000000						
00001340	00000000 00000000			706+	DS	FD	gap
				707+*			
00001348				708+X5	DS	0F	
00001348	E310 5010 0014		00000010	709+	LGF	R1, V2ADDR	load v2 source
0000134E	E761 0000 0806		00000000	710+	VL	v22, 0(R1)	use v22 to test decoder
00001354	E310 5014 0014		00000014	711+	LGF	R1, V3ADDR	load v3 source
0000135A	E771 0000 0806		00000000	712+	VL	v23, 0(R1)	use v23 to test decoder
00001360	E766 7000 0E68			713+	VN	V22, V22, V23	test instruction (dest is a source)
00001366	E760 5028 080E		00001330	714+	VST	V22, V105	save v1 output
0000136C	07FB			715+	BR	R11	return
00001370				716+RE5	DC	0F	xl16 expected result
00001370				717+	DROP	R5	
00001370	F0E0D000 B0A09000			718	DC	XL16' F0E0D000B0A09000 7060500030201000'	result t
00001378	70605000 30201000						
00001380	FFFFFFF0 FFFFFFF0			719	DC	XL16' FFFFFFF0FFFFFFF0 FFFFFFF0FFFFFFFF'	v2
00001388	FFFFFFF0 FFFFFFFF						
00001390	F0E0D0C0 B0A09080			720	DC	XL16' F0E0D0C0B0A09080 7060504030201000'	v3
00001398	70605040 30201000						
				721			
				722 *			
				723 *	VNC	- Vector AND with Complement	
				724 *			
				725			
000013A0				726	VRR_C	VNC	
000013A0		000013A0		727+	DS	0FD	
000013A0	000013E0			728+	USING	*, R5	base for test data and test routine
000013A4	0006			729+T6	DC	A(X6)	address of test routine
000013A6	00			730+	DC	H' 6'	test number
000013A7	00			731+	DC	X' 00'	
000013A8	E5D5C340 40404040			732+	DC	HL1' 00'	m field
000013B0	00001418			733+	DC	CL8' VNC'	instruction name
000013B4	00001428			734+	DC	A(RE6+16)	address of v2 source
000013B8	00000010			735+	DC	A(RE6+32)	address of v3 source
000013BC	00001408			736+	DC	A(16)	result length
000013C0	00000000 00000000			737+REA6	DC	A(RE6)	result address
000013C8	00000000 00000000			738+	DS	FD	gap
000013D0	00000000 00000000			739+V106	DS	XL16	V1 output
000013D8	00000000 00000000			740+	DS	FD	gap
				741+*			
000013E0				742+X6	DS	0F	
000013E0	E310 5010 0014		00000010	743+	LGF	R1, V2ADDR	load v2 source
000013E6	E761 0000 0806		00000000	744+	VL	v22, 0(R1)	use v22 to test decoder
000013EC	E310 5014 0014		00000014	745+	LGF	R1, V3ADDR	load v3 source
000013F2	E771 0000 0806		00000000	746+	VL	v23, 0(R1)	use v23 to test decoder
000013F8	E766 7000 0E69			747+	VNC	V22, V22, V23	test instruction (dest is a source)
000013FE	E760 5028 080E		000013C8	748+	VST	V22, V106	save v1 output
00001404	07FB			749+	BR	R11	return
00001408				750+RE6	DC	0F	xl16 expected result
00001408				751+	DROP	R5	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001408	00000000 00000000			752	DC	XL16' 0000000000000000 0000000000000000'	result
00001410	00000000 00000000						
00001418	00000000 00000000			753	DC	XL16' 0000000000000000 0000000000000000'	v2
00001420	00000000 00000000						
00001428	00000000 00000000			754	DC	XL16' 0000000000000000 0000000000000000'	v3
00001430	00000000 00000000						
				755			
				756	VRR_C	VNC	
00001438				757+	DS	OFD	
00001438		00001438		758+	USING	*, R5	base for test data and test routine
00001438	00001478			759+T7	DC	A(X7)	address of test routine
0000143C	0007			760+	DC	H' 7'	test number
0000143E	00			761+	DC	X' 00'	
0000143F	00			762+	DC	HL1' 00'	m field
00001440	E5D5C340 40404040			763+	DC	CL8' VNC'	instruction name
00001448	000014B0			764+	DC	A(RE7+16)	address of v2 source
0000144C	000014C0			765+	DC	A(RE7+32)	address of v3 source
00001450	00000010			766+	DC	A(16)	result length
00001454	000014A0			767+REA7	DC	A(RE7)	result address
00001458	00000000 00000000			768+	DS	FD	gap
00001460	00000000 00000000			769+V107	DS	XL16	V1 output
00001468	00000000 00000000						
00001470	00000000 00000000			770+	DS	FD	gap
				771+*			
00001478				772+X7	DS	OF	
00001478	E310 5010 0014		00000010	773+	LGF	R1, V2ADDR	load v2 source
0000147E	E761 0000 0806		00000000	774+	VL	v22, 0(R1)	use v22 to test decoder
00001484	E310 5014 0014		00000014	775+	LGF	R1, V3ADDR	load v3 source
0000148A	E771 0000 0806		00000000	776+	VL	v23, 0(R1)	use v23 to test decoder
00001490	E766 7000 0E69			777+	VNC	V22, V22, V23	test instruction (dest is a source)
00001496	E760 5028 080E		00001460	778+	VST	V22, V107	save v1 output
0000149C	07FB			779+	BR	R11	return
000014A0				780+RE7	DC	OF	xl16 expected result
000014A0				781+	DROP	R5	
000014A0	00000000 00000000			782	DC	XL16' 0000000000000000 0000000000000000'	result
000014A8	00000000 00000000						
000014B0	FFFFFFFF FFFFFFFF			783	DC	XL16' FFFFFFFFFFFFFFFFFF FFFFFFFFFFFFFFFFFF'	v2
000014B8	FFFFFFFF FFFFFFFF						
000014C0	FFFFFFFF FFFFFFFF			784	DC	XL16' FFFFFFFFFFFFFFFFFF FFFFFFFFFFFFFFFFFF'	v3
000014C8	FFFFFFFF FFFFFFFF						
				785			
				786	VRR_C	VNC	
000014D0				787+	DS	OFD	
000014D0		000014D0		788+	USING	*, R5	base for test data and test routine
000014D0	00001510			789+T8	DC	A(X8)	address of test routine
000014D4	0008			790+	DC	H' 8'	test number
000014D6	00			791+	DC	X' 00'	
000014D7	00			792+	DC	HL1' 00'	m field
000014D8	E5D5C340 40404040			793+	DC	CL8' VNC'	instruction name
000014E0	00001548			794+	DC	A(RE8+16)	address of v2 source
000014E4	00001558			795+	DC	A(RE8+32)	address of v3 source
000014E8	00000010			796+	DC	A(16)	result length
000014EC	00001538			797+REA8	DC	A(RE8)	result address
000014F0	00000000 00000000			798+	DS	FD	gap
000014F8	00000000 00000000			799+V108	DS	XL16	V1 output
00001500	00000000 00000000						

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001508	00000000 00000000			800+ 801+*	DS	FD	gap
00001510				802+X8	DS	0F	
00001510	E310 5010 0014		00000010	803+	LGF	R1, V2ADDR	load v2 source
00001516	E761 0000 0806		00000000	804+	VL	v22, 0(R1)	use v22 to test decoder
0000151C	E310 5014 0014		00000014	805+	LGF	R1, V3ADDR	load v3 source
00001522	E771 0000 0806		00000000	806+	VL	v23, 0(R1)	use v23 to test decoder
00001528	E766 7000 0E69			807+	VNC	V22, V22, V23	test instruction (dest is a source)
0000152E	E760 5028 080E		000014F8	808+	VST	V22, V108	save v1 output
00001534	07FB			809+	BR	R11	return
00001538				810+RE8	DC	0F	xl16 expected result
00001538				811+	DROP	R5	
00001538	00000000 00000000			812	DC	XL16' 0000000000000000 0000000000000000'	result t
00001540	00000000 00000000						
00001548	00010203 04050607			813	DC	XL16' 0001020304050607 08090A0B0C0D0E0F'	v2
00001550	08090A0B 0C0D0E0F						
00001558	FFFFFFFF FFFFFFFF			814	DC	XL16' FFFFFFFFFFFFFFFFFF FFFFFFFFFFFFFFFFFF'	v3
00001560	FFFFFFFF FFFFFFFF						
				815			
00001568				816	VRR_C	VNC	
00001568		00001568		817+	DS	0FD	
00001568	000015A8			818+	USING	*, R5	base for test data and test routine
0000156C	0009			819+T9	DC	A(X9)	address of test routine
0000156E	00			820+	DC	H' 9'	test number
0000156F	00			821+	DC	X' 00'	
00001570	E5D5C340 40404040			822+	DC	HL1' 00'	m field
00001578	000015E0			823+	DC	CL8' VNC'	instruction name
0000157C	000015F0			824+	DC	A(RE9+16)	address of v2 source
00001580	00000010			825+	DC	A(RE9+32)	address of v3 source
00001584	000015D0			826+	DC	A(16)	result length
00001588	00000000 00000000			827+REA9	DC	A(RE9)	result address
00001590	00000000 00000000			828+	DS	FD	gap
00001598	00000000 00000000			829+V109	DS	XL16	V1 output
000015A0	00000000 00000000			830+	DS	FD	gap
				831+*			
000015A8				832+X9	DS	0F	
000015A8	E310 5010 0014		00000010	833+	LGF	R1, V2ADDR	load v2 source
000015AE	E761 0000 0806		00000000	834+	VL	v22, 0(R1)	use v22 to test decoder
000015B4	E310 5014 0014		00000014	835+	LGF	R1, V3ADDR	load v3 source
000015BA	E771 0000 0806		00000000	836+	VL	v23, 0(R1)	use v23 to test decoder
000015C0	E766 7000 0E69			837+	VNC	V22, V22, V23	test instruction (dest is a source)
000015C6	E760 5028 080E		00001590	838+	VST	V22, V109	save v1 output
000015CC	07FB			839+	BR	R11	return
000015D0				840+RE9	DC	0F	xl16 expected result
000015D0				841+	DROP	R5	
000015D0	0F1F2F3F 4F5F6F7F			842	DC	XL16' 0F1F2F3F4F5F6F7F 8F9FAFBFCFDFEFFF'	result t
000015D8	8F9FAFBF CFDFEFFF						
000015E0	FFFFFFFF FFFFFFFF			843	DC	XL16' FFFFFFFFFFFFFFFFFF FFFFFFFFFFFFFFFFFF'	v2
000015E8	FFFFFFFF FFFFFFFF						
000015F0	F0E0D0C0 B0A09080			844	DC	XL16' F0E0D0C0B0A09080 7060504030201000'	v3
000015F8	70605040 30201000						
				845			
00001600				846	VRR_C	VNC	
00001600		00001600		847+	DS	0FD	
				848+	USING	*, R5	base for test data and test routine

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001600	00001640			849+T10	DC	A(X10)	address of test routine
00001604	000A			850+	DC	H' 10'	test number
00001606	00			851+	DC	X' 00'	
00001607	00			852+	DC	HL1' 00'	m field
00001608	E5D5C340 40404040			853+	DC	CL8' VNC'	instruction name
00001610	00001678			854+	DC	A(RE10+16)	address of v2 source
00001614	00001688			855+	DC	A(RE10+32)	address of v3 source
00001618	00000010			856+	DC	A(16)	result length
0000161C	00001668			857+REA10	DC	A(RE10)	result address
00001620	00000000 00000000			858+	DS	FD	gap
00001628	00000000 00000000			859+V1010	DS	XL16	V1 output
00001630	00000000 00000000						
00001638	00000000 00000000			860+	DS	FD	gap
				861+*			
00001640				862+X10	DS	0F	
00001640	E310 5010 0014		00000010	863+	LGF	R1, V2ADDR	load v2 source
00001646	E761 0000 0806		00000000	864+	VL	v22, 0(R1)	use v22 to test decoder
0000164C	E310 5014 0014		00000014	865+	LGF	R1, V3ADDR	load v3 source
00001652	E771 0000 0806		00000000	866+	VL	v23, 0(R1)	use v23 to test decoder
00001658	E766 7000 0E69			867+	VNC	V22, V22, V23	test instruction (dest is a source)
0000165E	E760 5028 080E		00001628	868+	VST	V22, V1010	save v1 output
00001664	07FB			869+	BR	R11	return
00001668				870+RE10	DC	0F	xl16 expected result
00001668				871+	DROP	R5	
00001668	0F1F2F00 4F5F6F00			872	DC	XL16' 0F1F2F004F5F6F00 8F9FAF00CFDFEFFF'	result t
00001670	8F9FAF00 CFDFEFFF						
00001678	FFFFFFF0 FFFFFFFF00			873	DC	XL16' FFFFFFFF00FFFFFFF00 FFFFFFFF00FFFFFFF'	v2
00001680	FFFFFFF0 FFFFFFFF						
00001688	F0E0D0C0 B0A09080			874	DC	XL16' F0E0D0C0B0A09080 7060504030201000'	v3
00001690	70605040 30201000						
				875			
				876 *			
				877 *	V0	- Vector 0R	
				878 *			
				879			
				880	VRR_C	V0	
00001698				881+	DS	0FD	
00001698		00001698		882+	USING	*, R5	base for test data and test routine
00001698	000016D8			883+T11	DC	A(X11)	address of test routine
0000169C	000B			884+	DC	H' 11'	test number
0000169E	00			885+	DC	X' 00'	
0000169F	00			886+	DC	HL1' 00'	m field
000016A0	E5D64040 40404040			887+	DC	CL8' V0'	instruction name
000016A8	00001710			888+	DC	A(RE11+16)	address of v2 source
000016AC	00001720			889+	DC	A(RE11+32)	address of v3 source
000016B0	00000010			890+	DC	A(16)	result length
000016B4	00001700			891+REA11	DC	A(RE11)	result address
000016B8	00000000 00000000			892+	DS	FD	gap
000016C0	00000000 00000000			893+V1011	DS	XL16	V1 output
000016C8	00000000 00000000						
000016D0	00000000 00000000			894+	DS	FD	gap
				895+*			
000016D8				896+X11	DS	0F	
000016D8	E310 5010 0014		00000010	897+	LGF	R1, V2ADDR	load v2 source
000016DE	E761 0000 0806		00000000	898+	VL	v22, 0(R1)	use v22 to test decoder
000016E4	E310 5014 0014		00000014	899+	LGF	R1, V3ADDR	load v3 source

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000016EA	E771 0000 0806		00000000	900+	VL	v23, 0(R1)	use v23 to test decoder
000016F0	E766 7000 0E6A			901+	V0	V22, V22, V23	test instruction (dest is a source)
000016F6	E760 5028 080E		000016C0	902+	VST	V22, V1011	save v1 output
000016FC	07FB			903+	BR	R11	return
00001700				904+RE11	DC	0F	xl16 expected result
00001700				905+	DROP	R5	
00001700	00000000 00000000			906	DC	XL16' 0000000000000000 0000000000000000'	result t
00001708	00000000 00000000						
00001710	00000000 00000000			907	DC	XL16' 0000000000000000 0000000000000000'	v2
00001718	00000000 00000000						
00001720	00000000 00000000			908	DC	XL16' 0000000000000000 0000000000000000'	v3
00001728	00000000 00000000						
				909			
				910	VRR_C	V0	
00001730				911+	DS	0FD	
00001730		00001730		912+	USING	*, R5	base for test data and test routine
00001730	00001770			913+T12	DC	A(X12)	address of test routine
00001734	000C			914+	DC	H' 12'	test number
00001736	00			915+	DC	X' 00'	
00001737	00			916+	DC	HL1' 00'	m field
00001738	E5D64040 40404040			917+	DC	CL8' V0'	instruction name
00001740	000017A8			918+	DC	A(RE12+16)	address of v2 source
00001744	000017B8			919+	DC	A(RE12+32)	address of v3 source
00001748	00000010			920+	DC	A(16)	result length
0000174C	00001798			921+REA12	DC	A(RE12)	result address
00001750	00000000 00000000			922+	DS	FD	gap
00001758	00000000 00000000			923+V1012	DS	XL16	V1 output
00001760	00000000 00000000						
00001768	00000000 00000000			924+	DS	FD	gap
				925+*			
00001770				926+X12	DS	0F	
00001770	E310 5010 0014		00000010	927+	LGF	R1, V2ADDR	load v2 source
00001776	E761 0000 0806		00000000	928+	VL	v22, 0(R1)	use v22 to test decoder
0000177C	E310 5014 0014		00000014	929+	LGF	R1, V3ADDR	load v3 source
00001782	E771 0000 0806		00000000	930+	VL	v23, 0(R1)	use v23 to test decoder
00001788	E766 7000 0E6A			931+	V0	V22, V22, V23	test instruction (dest is a source)
0000178E	E760 5028 080E		00001758	932+	VST	V22, V1012	save v1 output
00001794	07FB			933+	BR	R11	return
00001798				934+RE12	DC	0F	xl16 expected result
00001798				935+	DROP	R5	
00001798	FFFFFFFF FFFFFFFF			936	DC	XL16' FFFFFFFFFFFFFFFFFF FFFFFFFFFFFFFFFFFF'	result t
000017A0	FFFFFFFF FFFFFFFF						
000017A8	FFFFFFFF FFFFFFFF			937	DC	XL16' FFFFFFFFFFFFFFFFFF FFFFFFFFFFFFFFFFFF'	v2
000017B0	FFFFFFFF FFFFFFFF						
000017B8	FFFFFFFF FFFFFFFF			938	DC	XL16' FFFFFFFFFFFFFFFFFF FFFFFFFFFFFFFFFFFF'	v3
000017C0	FFFFFFFF FFFFFFFF						
				939			
				940	VRR_C	V0	
000017C8				941+	DS	0FD	
000017C8		000017C8		942+	USING	*, R5	base for test data and test routine
000017C8	00001808			943+T13	DC	A(X13)	address of test routine
000017CC	000D			944+	DC	H' 13'	test number
000017CE	00			945+	DC	X' 00'	
000017CF	00			946+	DC	HL1' 00'	m field
000017D0	E5D64040 40404040			947+	DC	CL8' V0'	instruction name
000017D8	00001840			948+	DC	A(RE13+16)	address of v2 source

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000017DC	00001850			949+	DC	A(RE13+32)	address of v3 source
000017E0	00000010			950+	DC	A(16)	result length
000017E4	00001830			951+REA13	DC	A(RE13)	result address
000017E8	00000000 00000000			952+	DS	FD	gap
000017F0	00000000 00000000			953+V1013	DS	XL16	V1 output
000017F8	00000000 00000000						
00001800	00000000 00000000			954+	DS	FD	gap
				955+*			
00001808				956+X13	DS	0F	
00001808	E310 5010 0014		00000010	957+	LGF	R1, V2ADDR	load v2 source
0000180E	E761 0000 0806		00000000	958+	VL	v22, 0(R1)	use v22 to test decoder
00001814	E310 5014 0014		00000014	959+	LGF	R1, V3ADDR	load v3 source
0000181A	E771 0000 0806		00000000	960+	VL	v23, 0(R1)	use v23 to test decoder
00001820	E766 7000 0E6A			961+	VO	V22, V22, V23	test instruction (dest is a source)
00001826	E760 5028 080E		000017F0	962+	VST	V22, V1013	save v1 output
0000182C	07FB			963+	BR	R11	return
00001830				964+RE13	DC	0F	xl16 expected result
00001830				965+	DROP	R5	
00001830	FFFFFFFF FFFFFFFF			966	DC	XL16' FFFFFFFFFFFFFFFFFF FFFFFFFFFFFFFFFFFF'	result t
00001838	FFFFFFFF FFFFFFFF						
00001840	00010203 04050607			967	DC	XL16' 0001020304050607 08090A0B0C0D0E0F'	v2
00001848	08090A0B 0C0D0E0F						
00001850	FFFFFFFF FFFFFFFF			968	DC	XL16' FFFFFFFFFFFFFFFFFF FFFFFFFFFFFFFFFFFF'	v3
00001858	FFFFFFFF FFFFFFFF						
				969			
				970	VRR_C	VO	
00001860				971+	DS	0FD	
00001860		00001860		972+	USING	*, R5	base for test data and test routine
00001860	000018A0			973+T14	DC	A(X14)	address of test routine
00001864	000E			974+	DC	H' 14'	test number
00001866	00			975+	DC	X' 00'	
00001867	00			976+	DC	HL1' 00'	m field
00001868	E5D64040 40404040			977+	DC	CL8' V0'	instruction name
00001870	000018D8			978+	DC	A(RE14+16)	address of v2 source
00001874	000018E8			979+	DC	A(RE14+32)	address of v3 source
00001878	00000010			980+	DC	A(16)	result length
0000187C	000018C8			981+REA14	DC	A(RE14)	result address
00001880	00000000 00000000			982+	DS	FD	gap
00001888	00000000 00000000			983+V1014	DS	XL16	V1 output
00001890	00000000 00000000						
00001898	00000000 00000000			984+	DS	FD	gap
				985+*			
000018A0				986+X14	DS	0F	
000018A0	E310 5010 0014		00000010	987+	LGF	R1, V2ADDR	load v2 source
000018A6	E761 0000 0806		00000000	988+	VL	v22, 0(R1)	use v22 to test decoder
000018AC	E310 5014 0014		00000014	989+	LGF	R1, V3ADDR	load v3 source
000018B2	E771 0000 0806		00000000	990+	VL	v23, 0(R1)	use v23 to test decoder
000018B8	E766 7000 0E6A			991+	VO	V22, V22, V23	test instruction (dest is a source)
000018BE	E760 5028 080E		00001888	992+	VST	V22, V1014	save v1 output
000018C4	07FB			993+	BR	R11	return
000018C8				994+RE14	DC	0F	xl16 expected result
000018C8				995+	DROP	R5	
000018C8	FFFFFFFF FFFFFFFF			996	DC	XL16' FFFFFFFFFFFFFFFFFF FFFFFFFFFFFFFFFFFF'	result t
000018D0	FFFFFFFF FFFFFFFF						
000018D8	FFFFFFFF FFFFFFFF			997	DC	XL16' FFFFFFFFFFFFFFFFFF FFFFFFFFFFFFFFFFFF'	v2
000018E0	FFFFFFFF FFFFFFFF						

LOC	OBJECT CODE	ADDR1	ADDR2	STMT				
000018E8	F0E0D0C0 B0A09080			998	DC	XL16' F0E0D0C0B0A09080 7060504030201000'	v3	
000018F0	70605040 30201000							
				999				
				1000	VRR_C	V0		
000018F8				1001+	DS	0FD		
000018F8		000018F8		1002+	USING	*, R5	base for test data and test routine	
000018F8	00001938			1003+T15	DC	A(X15)	address of test routine	
000018FC	000F			1004+	DC	H' 15'	test number	
000018FE	00			1005+	DC	X' 00'		
000018FF	00			1006+	DC	HL1' 00'	m field	
00001900	E5D64040 40404040			1007+	DC	CL8' V0'	instruction name	
00001908	00001970			1008+	DC	A(RE15+16)	address of v2 source	
0000190C	00001980			1009+	DC	A(RE15+32)	address of v3 source	
00001910	00000010			1010+	DC	A(16)	result length	
00001914	00001960			1011+REA15	DC	A(RE15)	result address	
00001918	00000000 00000000			1012+	DS	FD	gap	
00001920	00000000 00000000			1013+V1015	DS	XL16	V1 output	
00001928	00000000 00000000							
00001930	00000000 00000000			1014+	DS	FD	gap	
				1015+*				
00001938				1016+X15	DS	0F		
00001938	E310 5010 0014		00000010	1017+	LGF	R1, V2ADDR	load v2 source	
0000193E	E761 0000 0806		00000000	1018+	VL	v22, 0(R1)	use v22 to test decoder	
00001944	E310 5014 0014		00000014	1019+	LGF	R1, V3ADDR	load v3 source	
0000194A	E771 0000 0806		00000000	1020+	VL	v23, 0(R1)	use v23 to test decoder	
00001950	E766 7000 0E6A			1021+	V0	V22, V22, V23	test instruction (dest is a source)	
00001956	E760 5028 080E		00001920	1022+	VST	V22, V1015	save v1 output	
0000195C	07FB			1023+	BR	R11	return	
00001960				1024+RE15	DC	0F	xl16 expected result	
00001960				1025+	DROP	R5		
00001960	FFFFFFFFC0 FFFFFFFF80			1026	DC	XL16' FFFFFFFFC0FFFFFFF80 FFFFFFFF40FFFFFFFF'	result t	
00001968	FFFFFFFF40 FFFFFFFF							
00001970	FFFFFFFF00 FFFFFFFF00			1027	DC	XL16' FFFFFFFF00FFFFFFF00 FFFFFFFF00FFFFFFFF'	v2	
00001978	FFFFFFFF00 FFFFFFFF							
00001980	F0E0D0C0 B0A09080			1028	DC	XL16' F0E0D0C0B0A09080 7060504030201000'	v3	
00001988	70605040 30201000							
				1029				
				1030 *				
				1031 *	VN0	- Vector NOR		
				1032 *				
				1033				
				1034	VRR_C	VN0		
00001990				1035+	DS	0FD		
00001990		00001990		1036+	USING	*, R5	base for test data and test routine	
00001990	000019D0			1037+T16	DC	A(X16)	address of test routine	
00001994	0010			1038+	DC	H' 16'	test number	
00001996	00			1039+	DC	X' 00'		
00001997	00			1040+	DC	HL1' 00'	m field	
00001998	E5D5D640 40404040			1041+	DC	CL8' VN0'	instruction name	
000019A0	00001A08			1042+	DC	A(RE16+16)	address of v2 source	
000019A4	00001A18			1043+	DC	A(RE16+32)	address of v3 source	
000019A8	00000010			1044+	DC	A(16)	result length	
000019AC	000019F8			1045+REA16	DC	A(RE16)	result address	
000019B0	00000000 00000000			1046+	DS	FD	gap	
000019B8	00000000 00000000			1047+V1016	DS	XL16	V1 output	
000019C0	00000000 00000000							

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000019C8	00000000 00000000			1048+ 1049+*	DS	FD	gap
000019D0				1050+X16	DS	0F	
000019D0	E310 5010 0014		00000010	1051+	LGF	R1, V2ADDR	load v2 source
000019D6	E761 0000 0806		00000000	1052+	VL	v22, 0(R1)	use v22 to test decoder
000019DC	E310 5014 0014		00000014	1053+	LGF	R1, V3ADDR	load v3 source
000019E2	E771 0000 0806		00000000	1054+	VL	v23, 0(R1)	use v23 to test decoder
000019E8	E766 7000 0E6B			1055+	VNO	V22, V22, V23	test instruction (dest is a source)
000019EE	E760 5028 080E		000019B8	1056+	VST	V22, V1016	save v1 output
000019F4	07FB			1057+	BR	R11	return
000019F8				1058+RE16	DC	0F	xl16 expected result
000019F8				1059+	DROP	R5	
000019F8	FFFFFFFF FFFFFFFF			1060	DC	XL16' FFFFFFFFFFFFFFFFFF FFFFFFFFFFFFFFFFFF'	result t
00001A00	FFFFFFFF FFFFFFFF						
00001A08	00000000 00000000			1061	DC	XL16' 0000000000000000 0000000000000000'	v2
00001A10	00000000 00000000						
00001A18	00000000 00000000			1062	DC	XL16' 0000000000000000 0000000000000000'	v3
00001A20	00000000 00000000						
				1063			
				1064	VRR_C	VNO	
00001A28				1065+	DS	0FD	
00001A28		00001A28		1066+	USING	*, R5	base for test data and test routine
00001A28	00001A68			1067+T17	DC	A(X17)	address of test routine
00001A2C	0011			1068+	DC	H' 17'	test number
00001A2E	00			1069+	DC	X' 00'	
00001A2F	00			1070+	DC	HL1' 00'	m field
00001A30	E5D5D640 40404040			1071+	DC	CL8' VNO'	instruction name
00001A38	00001AA0			1072+	DC	A(RE17+16)	address of v2 source
00001A3C	00001AB0			1073+	DC	A(RE17+32)	address of v3 source
00001A40	00000010			1074+	DC	A(16)	result length
00001A44	00001A90			1075+REA17	DC	A(RE17)	result address
00001A48	00000000 00000000			1076+	DS	FD	gap
00001A50	00000000 00000000			1077+V1017	DS	XL16	V1 output
00001A58	00000000 00000000						
00001A60	00000000 00000000			1078+	DS	FD	gap
				1079+*			
00001A68				1080+X17	DS	0F	
00001A68	E310 5010 0014		00000010	1081+	LGF	R1, V2ADDR	load v2 source
00001A6E	E761 0000 0806		00000000	1082+	VL	v22, 0(R1)	use v22 to test decoder
00001A74	E310 5014 0014		00000014	1083+	LGF	R1, V3ADDR	load v3 source
00001A7A	E771 0000 0806		00000000	1084+	VL	v23, 0(R1)	use v23 to test decoder
00001A80	E766 7000 0E6B			1085+	VNO	V22, V22, V23	test instruction (dest is a source)
00001A86	E760 5028 080E		00001A50	1086+	VST	V22, V1017	save v1 output
00001A8C	07FB			1087+	BR	R11	return
00001A90				1088+RE17	DC	0F	xl16 expected result
00001A90				1089+	DROP	R5	
00001A90	00000000 00000000			1090	DC	XL16' 0000000000000000 0000000000000000'	result t
00001A98	00000000 00000000						
00001AA0	FFFFFFFF FFFFFFFF			1091	DC	XL16' FFFFFFFFFFFFFFFFFF FFFFFFFFFFFFFFFFFF'	v2
00001AA8	FFFFFFFF FFFFFFFF						
00001AB0	FFFFFFFF FFFFFFFF			1092	DC	XL16' FFFFFFFFFFFFFFFFFF FFFFFFFFFFFFFFFFFF'	v3
00001AB8	FFFFFFFF FFFFFFFF						
				1093			
				1094	VRR_C	VNO	
00001AC0				1095+	DS	0FD	
00001AC0		00001AC0		1096+	USING	*, R5	base for test data and test routine

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001AC0	00001B00			1097+T18	DC	A(X18)	address of test routine
00001AC4	0012			1098+	DC	H' 18'	test number
00001AC6	00			1099+	DC	X' 00'	
00001AC7	00			1100+	DC	HL1' 00'	m field
00001AC8	E5D5D640 40404040			1101+	DC	CL8' VN0'	instruction name
00001AD0	00001B38			1102+	DC	A(RE18+16)	address of v2 source
00001AD4	00001B48			1103+	DC	A(RE18+32)	address of v3 source
00001AD8	00000010			1104+	DC	A(16)	result length
00001ADC	00001B28			1105+REA18	DC	A(RE18)	result address
00001AE0	00000000 00000000			1106+	DS	FD	gap
00001AE8	00000000 00000000			1107+V1018	DS	XL16	V1 output
00001AF0	00000000 00000000						
00001AF8	00000000 00000000			1108+	DS	FD	gap
				1109+*			
00001B00				1110+X18	DS	0F	
00001B00	E310 5010 0014		00000010	1111+	LGF	R1, V2ADDR	load v2 source
00001B06	E761 0000 0806		00000000	1112+	VL	v22, 0(R1)	use v22 to test decoder
00001B0C	E310 5014 0014		00000014	1113+	LGF	R1, V3ADDR	load v3 source
00001B12	E771 0000 0806		00000000	1114+	VL	v23, 0(R1)	use v23 to test decoder
00001B18	E766 7000 0E6B			1115+	VN0	V22, V22, V23	test instruction (dest is a source)
00001B1E	E760 5028 080E		00001AE8	1116+	VST	V22, V1018	save v1 output
00001B24	07FB			1117+	BR	R11	return
00001B28				1118+RE18	DC	0F	xl16 expected result
00001B28				1119+	DROP	R5	
00001B28	00000000 00000000			1120	DC	XL16' 0000000000000000 0000000000000000'	result
00001B30	00000000 00000000						
00001B38	00010203 04050607			1121	DC	XL16' 0001020304050607 08090A0B0C0D0E0F'	v2
00001B40	08090A0B 0C0D0E0F						
00001B48	FFFFFFFF FFFFFFFF			1122	DC	XL16' FFFFFFFFFFFFFFFFFF FFFFFFFFFFFFFFFFFF'	v3
00001B50	FFFFFFFF FFFFFFFF						
				1123			
				1124	VRR_C	VN0	
00001B58				1125+	DS	0FD	
00001B58		00001B58		1126+	USING	*, R5	base for test data and test routine
00001B58	00001B98			1127+T19	DC	A(X19)	address of test routine
00001B5C	0013			1128+	DC	H' 19'	test number
00001B5E	00			1129+	DC	X' 00'	
00001B5F	00			1130+	DC	HL1' 00'	m field
00001B60	E5D5D640 40404040			1131+	DC	CL8' VN0'	instruction name
00001B68	00001BD0			1132+	DC	A(RE19+16)	address of v2 source
00001B6C	00001BE0			1133+	DC	A(RE19+32)	address of v3 source
00001B70	00000010			1134+	DC	A(16)	result length
00001B74	00001BC0			1135+REA19	DC	A(RE19)	result address
00001B78	00000000 00000000			1136+	DS	FD	gap
00001B80	00000000 00000000			1137+V1019	DS	XL16	V1 output
00001B88	00000000 00000000						
00001B90	00000000 00000000			1138+	DS	FD	gap
				1139+*			
00001B98				1140+X19	DS	0F	
00001B98	E310 5010 0014		00000010	1141+	LGF	R1, V2ADDR	load v2 source
00001B9E	E761 0000 0806		00000000	1142+	VL	v22, 0(R1)	use v22 to test decoder
00001BA4	E310 5014 0014		00000014	1143+	LGF	R1, V3ADDR	load v3 source
00001BAA	E771 0000 0806		00000000	1144+	VL	v23, 0(R1)	use v23 to test decoder
00001BB0	E766 7000 0E6B			1145+	VN0	V22, V22, V23	test instruction (dest is a source)
00001BB6	E760 5028 080E		00001B80	1146+	VST	V22, V1019	save v1 output
00001BBC	07FB			1147+	BR	R11	return

LOC	OBJECT	CODE	ADDR1	ADDR2	STMT			
00001BC0					1148+RE19	DC	0F	xl16 expected result
00001BC0					1149+	DROP	R5	
00001BC0	00000000	00000000			1150	DC	XL16' 0000000000000000 0000000000000000'	result
00001BC8	00000000	00000000						
00001BD0	FFFFFFFF	FFFFFFFF			1151	DC	XL16' FFFFFFFFFFFFFFFFFF FFFFFFFFFFFFFFFFFF'	v2
00001BD8	FFFFFFFF	FFFFFFFF						
00001BE0	F0E0D0C0	B0A09080			1152	DC	XL16' F0E0D0C0B0A09080 7060504030201000'	v3
00001BE8	70605040	30201000						
					1153			
00001BF0					1154	VRR_C	VN0	
00001BF0			00001BF0		1155+	DS	0FD	
00001BF0	00001C30				1156+	USING	*, R5	base for test data and test routine
00001BF4	0014				1157+T20	DC	A(X20)	address of test routine
00001BF6	00				1158+	DC	H' 20'	test number
00001BF7	00				1159+	DC	X' 00'	
00001BF8	E5D5D640	40404040			1160+	DC	HL1' 00'	m field
00001C00	00001C68				1161+	DC	CL8' VN0'	instruction name
00001C04	00001C78				1162+	DC	A(RE20+16)	address of v2 source
00001C08	00000010				1163+	DC	A(RE20+32)	address of v3 source
00001C0C	00001C58				1164+	DC	A(16)	result length
00001C10	00000000	00000000			1165+REA20	DC	A(RE20)	result address
00001C18	00000000	00000000			1166+	DS	FD	gap
00001C20	00000000	00000000			1167+V1020	DS	XL16	V1 output
00001C28	00000000	00000000						
					1168+	DS	FD	gap
					1169+*			
00001C30					1170+X20	DS	0F	
00001C30	E310 5010 0014		00000010		1171+	LGF	R1, V2ADDR	load v2 source
00001C36	E761 0000 0806		00000000		1172+	VL	v22, 0(R1)	use v22 to test decoder
00001C3C	E310 5014 0014		00000014		1173+	LGF	R1, V3ADDR	load v3 source
00001C42	E771 0000 0806		00000000		1174+	VL	v23, 0(R1)	use v23 to test decoder
00001C48	E766 7000 0E6B				1175+	VN0	V22, V22, V23	test instruction (dest is a source)
00001C4E	E760 5028 080E		00001C18		1176+	VST	V22, V1020	save v1 output
00001C54	07FB				1177+	BR	R11	return
00001C58					1178+RE20	DC	0F	xl16 expected result
00001C58					1179+	DROP	R5	
00001C58	0000003F	0000007F			1180	DC	XL16' 0000003F0000007F 000000BF00000000'	result
00001C60	000000BF	00000000						
00001C68	FFFFFF00	FFFFFF00			1181	DC	XL16' FFFFFFF0FFFFFFF0 FFFFFFF0FFFFFFF'	v2
00001C70	FFFFFF00	FFFFFFF'						
00001C78	F0E0D0C0	B0A09080			1182	DC	XL16' F0E0D0C0B0A09080 7060504030201000'	v3
00001C80	70605040	30201000						
					1183			
					1184 *			
					1185 *	VNX	- Vector Not Exclusive OR	
					1186 *			
					1187			
00001C88					1188	VRR_C	VNX	
00001C88			00001C88		1189+	DS	0FD	
00001C88	00001CC8				1190+	USING	*, R5	base for test data and test routine
00001C8C	0015				1191+T21	DC	A(X21)	address of test routine
00001C8E	00				1192+	DC	H' 21'	test number
00001C8F	00				1193+	DC	X' 00'	
00001C90	E5D5E740	40404040			1194+	DC	HL1' 00'	m field
00001C98	00001D00				1195+	DC	CL8' VNX'	instruction name
					1196+	DC	A(RE21+16)	address of v2 source

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001C9C	00001D10			1197+	DC	A(RE21+32)	address of v3 source
00001CA0	00000010			1198+	DC	A(16)	result length
00001CA4	00001CF0			1199+REA21	DC	A(RE21)	result address
00001CA8	00000000 00000000			1200+	DS	FD	gap
00001CB0	00000000 00000000			1201+V1021	DS	XL16	V1 output
00001CB8	00000000 00000000						
00001CC0	00000000 00000000			1202+	DS	FD	gap
				1203+*			
00001CC8				1204+X21	DS	0F	
00001CC8	E310 5010 0014		00000010	1205+	LGF	R1, V2ADDR	load v2 source
00001CCE	E761 0000 0806		00000000	1206+	VL	v22, 0(R1)	use v22 to test decoder
00001CD4	E310 5014 0014		00000014	1207+	LGF	R1, V3ADDR	load v3 source
00001CDA	E771 0000 0806		00000000	1208+	VL	v23, 0(R1)	use v23 to test decoder
00001CE0	E766 7000 0E6C			1209+	VNX	V22, V22, V23	test instruction (dest is a source)
00001CE6	E760 5028 080E		00001CB0	1210+	VST	V22, V1021	save v1 output
00001CEC	07FB			1211+	BR	R11	return
00001CF0				1212+RE21	DC	0F	xl16 expected result
00001CF0				1213+	DROP	R5	
00001CF0	FFFFFFFF FFFFFFFF			1214	DC	XL16' FFFFFFFFFFFFFFFFFF FFFFFFFFFFFFFFFFFF'	result t
00001CF8	FFFFFFFF FFFFFFFF						
00001D00	00000000 00000000			1215	DC	XL16' 0000000000000000 0000000000000000'	v2
00001D08	00000000 00000000						
00001D10	00000000 00000000			1216	DC	XL16' 0000000000000000 0000000000000000'	v3
00001D18	00000000 00000000						
				1217			
				1218	VRR_C	VNX	
00001D20				1219+	DS	0FD	
00001D20		00001D20		1220+	USING	*, R5	base for test data and test routine
00001D20	00001D60			1221+T22	DC	A(X22)	address of test routine
00001D24	0016			1222+	DC	H' 22'	test number
00001D26	00			1223+	DC	X' 00'	
00001D27	00			1224+	DC	HL1' 00'	m field
00001D28	E5D5E740 40404040			1225+	DC	CL8' VNX'	instruction name
00001D30	00001D98			1226+	DC	A(RE22+16)	address of v2 source
00001D34	00001DA8			1227+	DC	A(RE22+32)	address of v3 source
00001D38	00000010			1228+	DC	A(16)	result length
00001D3C	00001D88			1229+REA22	DC	A(RE22)	result address
00001D40	00000000 00000000			1230+	DS	FD	gap
00001D48	00000000 00000000			1231+V1022	DS	XL16	V1 output
00001D50	00000000 00000000						
00001D58	00000000 00000000			1232+	DS	FD	gap
				1233+*			
00001D60				1234+X22	DS	0F	
00001D60	E310 5010 0014		00000010	1235+	LGF	R1, V2ADDR	load v2 source
00001D66	E761 0000 0806		00000000	1236+	VL	v22, 0(R1)	use v22 to test decoder
00001D6C	E310 5014 0014		00000014	1237+	LGF	R1, V3ADDR	load v3 source
00001D72	E771 0000 0806		00000000	1238+	VL	v23, 0(R1)	use v23 to test decoder
00001D78	E766 7000 0E6C			1239+	VNX	V22, V22, V23	test instruction (dest is a source)
00001D7E	E760 5028 080E		00001D48	1240+	VST	V22, V1022	save v1 output
00001D84	07FB			1241+	BR	R11	return
00001D88				1242+RE22	DC	0F	xl16 expected result
00001D88				1243+	DROP	R5	
00001D88	FFFFFFFF FFFFFFFF			1244	DC	XL16' FFFFFFFFFFFFFFFFFF FFFFFFFFFFFFFFFFFF'	result t
00001D90	FFFFFFFF FFFFFFFF						
00001D98	FFFFFFFF FFFFFFFF			1245	DC	XL16' FFFFFFFFFFFFFFFFFF FFFFFFFFFFFFFFFFFF'	v2
00001DA0	FFFFFFFF FFFFFFFF						

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001DA8	FFFFFFFF FFFFFFFF			1246	DC	XL16' FFFFFFFFFFFFFFFFFF FFFFFFFFFFFFFFFFFF'	v3
00001DB0	FFFFFFFF FFFFFFFF						
				1247			
				1248	VRR_C	VNX	
00001DB8				1249+	DS	OFD	
00001DB8		00001DB8		1250+	USING	*, R5	base for test data and test routine
00001DB8	00001DF8			1251+T23	DC	A(X23)	address of test routine
00001DBC	0017			1252+	DC	H' 23'	test number
00001DBE	00			1253+	DC	X' 00'	
00001DBF	00			1254+	DC	HL1' 00'	m field
00001DC0	E5D5E740 40404040			1255+	DC	CL8' VNX'	instruction name
00001DC8	00001E30			1256+	DC	A(RE23+16)	address of v2 source
00001DCC	00001E40			1257+	DC	A(RE23+32)	address of v3 source
00001DD0	00000010			1258+	DC	A(16)	result length
00001DD4	00001E20			1259+REA23	DC	A(RE23)	result address
00001DD8	00000000 00000000			1260+	DS	FD	gap
00001DE0	00000000 00000000			1261+V1023	DS	XL16	V1 output
00001DE8	00000000 00000000						
00001DF0	00000000 00000000			1262+	DS	FD	gap
				1263+*			
00001DF8				1264+X23	DS	OF	
00001DF8	E310 5010 0014		00000010	1265+	LGF	R1, V2ADDR	load v2 source
00001DFE	E761 0000 0806		00000000	1266+	VL	v22, 0(R1)	use v22 to test decoder
00001E04	E310 5014 0014		00000014	1267+	LGF	R1, V3ADDR	load v3 source
00001E0A	E771 0000 0806		00000000	1268+	VL	v23, 0(R1)	use v23 to test decoder
00001E10	E766 7000 0E6C			1269+	VNX	V22, V22, V23	test instruction (dest is a source)
00001E16	E760 5028 080E		00001DE0	1270+	VST	V22, V1023	save v1 output
00001E1C	07FB			1271+	BR	R11	return
00001E20				1272+RE23	DC	OF	xl16 expected result
00001E20				1273+	DROP	R5	
00001E20	00010203 04050607			1274	DC	XL16' 0001020304050607 08090A0B0C0D0E0F'	result t
00001E28	08090A0B 0C0D0E0F						
00001E30	00010203 04050607			1275	DC	XL16' 0001020304050607 08090A0B0C0D0E0F'	v2
00001E38	08090A0B 0C0D0E0F						
00001E40	FFFFFFFF FFFFFFFF			1276	DC	XL16' FFFFFFFFFFFFFFFFFF FFFFFFFFFFFFFFFFFF'	v3
00001E48	FFFFFFFF FFFFFFFF						
				1277			
				1278	VRR_C	VNX	
00001E50				1279+	DS	OFD	
00001E50		00001E50		1280+	USING	*, R5	base for test data and test routine
00001E50	00001E90			1281+T24	DC	A(X24)	address of test routine
00001E54	0018			1282+	DC	H' 24'	test number
00001E56	00			1283+	DC	X' 00'	
00001E57	00			1284+	DC	HL1' 00'	m field
00001E58	E5D5E740 40404040			1285+	DC	CL8' VNX'	instruction name
00001E60	00001EC8			1286+	DC	A(RE24+16)	address of v2 source
00001E64	00001ED8			1287+	DC	A(RE24+32)	address of v3 source
00001E68	00000010			1288+	DC	A(16)	result length
00001E6C	00001EB8			1289+REA24	DC	A(RE24)	result address
00001E70	00000000 00000000			1290+	DS	FD	gap
00001E78	00000000 00000000			1291+V1024	DS	XL16	V1 output
00001E80	00000000 00000000						
00001E88	00000000 00000000			1292+	DS	FD	gap
				1293+*			
00001E90				1294+X24	DS	OF	
00001E90	E310 5010 0014		00000010	1295+	LGF	R1, V2ADDR	load v2 source

LOC	OBJECT CODE	ADDR1	ADDR2	STMT				
00001E96	E761 0000 0806		00000000	1296+	VL	v22, 0(R1)	use v22 to test decoder	
00001E9C	E310 5014 0014		00000014	1297+	LGF	R1, V3ADDR	load v3 source	
00001EA2	E771 0000 0806		00000000	1298+	VL	v23, 0(R1)	use v23 to test decoder	
00001EA8	E766 7000 0E6C			1299+	VNX	V22, V22, V23	test instruction (dest is a source)	
00001EAE	E760 5028 080E		00001E78	1300+	VST	V22, V1024	save v1 output	
00001EB4	07FB			1301+	BR	R11	return	
00001EB8				1302+RE24	DC	0F	xl16 expected result	
00001EB8				1303+	DROP	R5		
00001EB8	F0E0D0C0 B0A09080			1304	DC	XL16' F0E0D0C0B0A09080 7060504030201000'	result t	
00001EC0	70605040 30201000							
00001EC8	FFFFFFFF FFFFFFFF			1305	DC	XL16' FFFFFFFFFFFFFFFFFF FFFFFFFFFFFFFFFFFF'	v2	
00001ED0	FFFFFFFF FFFFFFFF							
00001ED8	F0E0D0C0 B0A09080			1306	DC	XL16' F0E0D0C0B0A09080 7060504030201000'	v3	
00001EE0	70605040 30201000							
				1307				
				1308	VRR_C	VNX		
00001EE8				1309+	DS	0FD		
00001EE8		00001EE8		1310+	USING	*, R5	base for test data and test routine	
00001EE8	00001F28			1311+T25	DC	A(X25)	address of test routine	
00001EEC	0019			1312+	DC	H' 25'	test number	
00001EEE	00			1313+	DC	X' 00'		
00001EEF	00			1314+	DC	HL1' 00'	m field	
00001EF0	E5D5E740 40404040			1315+	DC	CL8' VNX'	instruction name	
00001EF8	00001F60			1316+	DC	A(RE25+16)	address of v2 source	
00001EFC	00001F70			1317+	DC	A(RE25+32)	address of v3 source	
00001F00	00000010			1318+	DC	A(16)	result length	
00001F04	00001F50			1319+REA25	DC	A(RE25)	result address	
00001F08	00000000 00000000			1320+	DS	FD	gap	
00001F10	00000000 00000000			1321+V1025	DS	XL16	V1 output	
00001F18	00000000 00000000							
00001F20	00000000 00000000			1322+	DS	FD	gap	
				1323+*				
00001F28				1324+X25	DS	0F		
00001F28	E310 5010 0014		00000010	1325+	LGF	R1, V2ADDR	load v2 source	
00001F2E	E761 0000 0806		00000000	1326+	VL	v22, 0(R1)	use v22 to test decoder	
00001F34	E310 5014 0014		00000014	1327+	LGF	R1, V3ADDR	load v3 source	
00001F3A	E771 0000 0806		00000000	1328+	VL	v23, 0(R1)	use v23 to test decoder	
00001F40	E766 7000 0E6C			1329+	VNX	V22, V22, V23	test instruction (dest is a source)	
00001F46	E760 5028 080E		00001F10	1330+	VST	V22, V1025	save v1 output	
00001F4C	07FB			1331+	BR	R11	return	
00001F50				1332+RE25	DC	0F	xl16 expected result	
00001F50				1333+	DROP	R5		
00001F50	F0E0D03F B0A0907F			1334	DC	XL16' F0E0D03FB0A0907F 706050BF30201000'	result t	
00001F58	706050BF 30201000							
00001F60	FFFFFF00 FFFFFFF00			1335	DC	XL16' FFFFFFF00FFFFFF00 FFFFFFF00FFFFFFF'	v2	
00001F68	FFFFFF00 FFFFFFFF							
00001F70	F0E0D0C0 B0A09080			1336	DC	XL16' F0E0D0C0B0A09080 7060504030201000'	v3	
00001F78	70605040 30201000							
				1337				
				1338	*-----			
				1339	* VX - Vector Exclusive OR			
				1340	*-----			
				1341				
				1342	VRR_C	VX		
00001F80				1343+	DS	0FD		
00001F80		00001F80		1344+	USING	*, R5	base for test data and test routine	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001F80	00001FC0			1345+T26	DC	A(X26)	address of test routine
00001F84	001A			1346+	DC	H' 26'	test number
00001F86	00			1347+	DC	X' 00'	
00001F87	00			1348+	DC	HL1' 00'	m field
00001F88	E5E74040 40404040			1349+	DC	CL8' VX'	instruction name
00001F90	00001FF8			1350+	DC	A(RE26+16)	address of v2 source
00001F94	00002008			1351+	DC	A(RE26+32)	address of v3 source
00001F98	00000010			1352+	DC	A(16)	result length
00001F9C	00001FE8			1353+REA26	DC	A(RE26)	result address
00001FA0	00000000 00000000			1354+	DS	FD	gap
00001FA8	00000000 00000000			1355+V1026	DS	XL16	V1 output
00001FB0	00000000 00000000						
00001FB8	00000000 00000000			1356+	DS	FD	gap
				1357+*			
00001FC0				1358+X26	DS	OF	
00001FC0	E310 5010 0014		00000010	1359+	LGF	R1, V2ADDR	load v2 source
00001FC6	E761 0000 0806		00000000	1360+	VL	v22, 0(R1)	use v22 to test decoder
00001FCC	E310 5014 0014		00000014	1361+	LGF	R1, V3ADDR	load v3 source
00001FD2	E771 0000 0806		00000000	1362+	VL	v23, 0(R1)	use v23 to test decoder
00001FD8	E766 7000 0E6D			1363+	VX	V22, V22, V23	test instruction (dest is a source)
00001FDE	E760 5028 080E		00001FA8	1364+	VST	V22, V1026	save v1 output
00001FE4	07FB			1365+	BR	R11	return
00001FE8				1366+RE26	DC	OF	xl16 expected result
00001FE8				1367+	DROP	R5	
00001FE8	00000000 00000000			1368	DC	XL16' 0000000000000000 0000000000000000'	result t
00001FF0	00000000 00000000						
00001FF8	00000000 00000000			1369	DC	XL16' 0000000000000000 0000000000000000'	v2
00002000	00000000 00000000						
00002008	00000000 00000000			1370	DC	XL16' 0000000000000000 0000000000000000'	v3
00002010	00000000 00000000						
				1371			
				1372	VRR_C	VX	
00002018				1373+	DS	OFD	
00002018		00002018		1374+	USING	*, R5	base for test data and test routine
00002018	00002058			1375+T27	DC	A(X27)	address of test routine
0000201C	001B			1376+	DC	H' 27'	test number
0000201E	00			1377+	DC	X' 00'	
0000201F	00			1378+	DC	HL1' 00'	m field
00002020	E5E74040 40404040			1379+	DC	CL8' VX'	instruction name
00002028	00002090			1380+	DC	A(RE27+16)	address of v2 source
0000202C	000020A0			1381+	DC	A(RE27+32)	address of v3 source
00002030	00000010			1382+	DC	A(16)	result length
00002034	00002080			1383+REA27	DC	A(RE27)	result address
00002038	00000000 00000000			1384+	DS	FD	gap
00002040	00000000 00000000			1385+V1027	DS	XL16	V1 output
00002048	00000000 00000000						
00002050	00000000 00000000			1386+	DS	FD	gap
				1387+*			
00002058				1388+X27	DS	OF	
00002058	E310 5010 0014		00000010	1389+	LGF	R1, V2ADDR	load v2 source
0000205E	E761 0000 0806		00000000	1390+	VL	v22, 0(R1)	use v22 to test decoder
00002064	E310 5014 0014		00000014	1391+	LGF	R1, V3ADDR	load v3 source
0000206A	E771 0000 0806		00000000	1392+	VL	v23, 0(R1)	use v23 to test decoder
00002070	E766 7000 0E6D			1393+	VX	V22, V22, V23	test instruction (dest is a source)
00002076	E760 5028 080E		00002040	1394+	VST	V22, V1027	save v1 output
0000207C	07FB			1395+	BR	R11	return

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00002080				1396+RE27	DC	0F	xl16 expected result
00002080				1397+	DROP	R5	
00002080	00000000 00000000			1398	DC	XL16' 0000000000000000 0000000000000000'	result
00002088	00000000 00000000						
00002090	FFFFFFFF FFFFFFFF			1399	DC	XL16' FFFFFFFF FFFFFFFF FFFFFFFF FFFFFFFF'	v2
00002098	FFFFFFFF FFFFFFFF						
000020A0	FFFFFFFF FFFFFFFF			1400	DC	XL16' FFFFFFFF FFFFFFFF FFFFFFFF FFFFFFFF'	v3
000020A8	FFFFFFFF FFFFFFFF						
				1401			
				1402	VRR_C	VX	
000020B0				1403+	DS	0FD	
000020B0		000020B0		1404+	USING	*, R5	base for test data and test routine
000020B0	000020F0			1405+T28	DC	A(X28)	address of test routine
000020B4	001C			1406+	DC	H' 28'	test number
000020B6	00			1407+	DC	X' 00'	
000020B7	00			1408+	DC	HL1' 00'	m field
000020B8	E5E74040 40404040			1409+	DC	CL8' VX'	instruction name
000020C0	00002128			1410+	DC	A(RE28+16)	address of v2 source
000020C4	00002138			1411+	DC	A(RE28+32)	address of v3 source
000020C8	00000010			1412+	DC	A(16)	result length
000020CC	00002118			1413+REA28	DC	A(RE28)	result address
000020D0	00000000 00000000			1414+	DS	FD	gap
000020D8	00000000 00000000			1415+V1028	DS	XL16	V1 output
000020E0	00000000 00000000						
000020E8	00000000 00000000			1416+	DS	FD	gap
				1417+*			
000020F0				1418+X28	DS	0F	
000020F0	E310 5010 0014		00000010	1419+	LGF	R1, V2ADDR	load v2 source
000020F6	E761 0000 0806		00000000	1420+	VL	v22, 0(R1)	use v22 to test decoder
000020FC	E310 5014 0014		00000014	1421+	LGF	R1, V3ADDR	load v3 source
00002102	E771 0000 0806		00000000	1422+	VL	v23, 0(R1)	use v23 to test decoder
00002108	E766 7000 0E6D			1423+	VX	V22, V22, V23	test instruction (dest is a source)
0000210E	E760 5028 080E		000020D8	1424+	VST	V22, V1028	save v1 output
00002114	07FB			1425+	BR	R11	return
00002118				1426+RE28	DC	0F	xl16 expected result
00002118				1427+	DROP	R5	
00002118	FFFEFD FC FBFAF9F8			1428	DC	XL16' FFFEFD FC FBFAF9F8 F7F6F5F4F3F2F1F0'	result
00002120	F7F6F5F4 F3F2F1F0						
00002128	00010203 04050607			1429	DC	XL16' 0001020304050607 08090A0B0C0D0E0F'	v2
00002130	08090A0B 0C0D0E0F						
00002138	FFFFFFFF FFFFFFFF			1430	DC	XL16' FFFFFFFF FFFFFFFF FFFFFFFF FFFFFFFF'	v3
00002140	FFFFFFFF FFFFFFFF						
				1431			
				1432	VRR_C	VX	
00002148				1433+	DS	0FD	
00002148		00002148		1434+	USING	*, R5	base for test data and test routine
00002148	00002188			1435+T29	DC	A(X29)	address of test routine
0000214C	001D			1436+	DC	H' 29'	test number
0000214E	00			1437+	DC	X' 00'	
0000214F	00			1438+	DC	HL1' 00'	m field
00002150	E5E74040 40404040			1439+	DC	CL8' VX'	instruction name
00002158	000021C0			1440+	DC	A(RE29+16)	address of v2 source
0000215C	000021D0			1441+	DC	A(RE29+32)	address of v3 source
00002160	00000010			1442+	DC	A(16)	result length
00002164	000021B0			1443+REA29	DC	A(RE29)	result address
00002168	00000000 00000000			1444+	DS	FD	gap

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00002170	00000000 00000000			1445+V1029	DS	XL16	V1 output
00002178	00000000 00000000						
00002180	00000000 00000000			1446+	DS	FD	gap
				1447+*			
00002188				1448+X29	DS	0F	
00002188	E310 5010 0014		00000010	1449+	LGF	R1, V2ADDR	load v2 source
0000218E	E761 0000 0806		00000000	1450+	VL	v22, 0(R1)	use v22 to test decoder
00002194	E310 5014 0014		00000014	1451+	LGF	R1, V3ADDR	load v3 source
0000219A	E771 0000 0806		00000000	1452+	VL	v23, 0(R1)	use v23 to test decoder
000021A0	E766 7000 0E6D			1453+	VX	V22, V22, V23	test instruction (dest is a source)
000021A6	E760 5028 080E		00002170	1454+	VST	V22, V1029	save v1 output
000021AC	07FB			1455+	BR	R11	return
000021B0				1456+RE29	DC	0F	xl16 expected result
000021B0				1457+	DROP	R5	
000021B0	0F1F2F3F 4F5F6F7F			1458	DC	XL16' 0F1F2F3F4F5F6F7F 8F9FAFBFCFDFEFFF'	result t
000021B8	8F9FAFBF CFDFEFFF						
000021C0	FFFFFFFF FFFFFFFF			1459	DC	XL16' FFFFFFFF00000000 FFFFFFFF00000000'	v2
000021C8	FFFFFFFF FFFFFFFF						
000021D0	F0E0D0C0 B0A09080			1460	DC	XL16' F0E0D0C0B0A09080 7060504030201000'	v3
000021D8	70605040 30201000						
				1461			
000021E0				1462	VRR_C	VX	
000021E0		000021E0		1463+	DS	0FD	
000021E0	00002220			1464+	USING	*, R5	base for test data and test routine
000021E4	001E			1465+T30	DC	A(X30)	address of test routine
000021E6	00			1466+	DC	H' 30'	test number
000021E7	00			1467+	DC	X' 00'	
000021E8	E5E74040 40404040			1468+	DC	HL1' 00'	m field
000021F0	00002258			1469+	DC	CL8' VX'	instruction name
000021F4	00002268			1470+	DC	A(RE30+16)	address of v2 source
000021F8	00000010			1471+	DC	A(RE30+32)	address of v3 source
000021FC	00002248			1472+	DC	A(16)	result length
00002200	00000000 00000000			1473+REA30	DC	A(RE30)	result address
00002208	00000000 00000000			1474+	DS	FD	gap
00002210	00000000 00000000			1475+V1030	DS	XL16	V1 output
00002218	00000000 00000000						
				1476+	DS	FD	gap
				1477+*			
00002220				1478+X30	DS	0F	
00002220	E310 5010 0014		00000010	1479+	LGF	R1, V2ADDR	load v2 source
00002226	E761 0000 0806		00000000	1480+	VL	v22, 0(R1)	use v22 to test decoder
0000222C	E310 5014 0014		00000014	1481+	LGF	R1, V3ADDR	load v3 source
00002232	E771 0000 0806		00000000	1482+	VL	v23, 0(R1)	use v23 to test decoder
00002238	E766 7000 0E6D			1483+	VX	V22, V22, V23	test instruction (dest is a source)
0000223E	E760 A008 080E		00002208	1484+	VST	V22, V1030	save v1 output
00002244	07FB			1485+	BR	R11	return
00002248				1486+RE30	DC	0F	xl16 expected result
00002248				1487+	DROP	R5	
00002248	0F1F2FC0 4F5F6F80			1488	DC	XL16' 0F1F2FC04F5F6F80 8F9FAF40CFDFEFFF'	result t
00002250	8F9FAF40 CFDFEFFF						
00002258	FFFFFFF0 FFFFFFFF00			1489	DC	XL16' FFFFFFFF00FFFFFFF00 FFFFFFFF00FFFFFFF'	v2
00002260	FFFFFFF0 FFFFFFFF						
00002268	F0E0D0C0 B0A09080			1490	DC	XL16' F0E0D0C0B0A09080 7060504030201000'	v3
00002270	70605040 30201000						
				1491			
				1492 *			

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
				1493 *	VNN	- Vector NAND	
				1494 *			
				1495			
				1496	VRR_C	VNN	
00002278				1497+	DS	OFD	
00002278		00002278		1498+	USING	*, R5	base for test data and test routine
00002278	000022B8			1499+T31	DC	A(X31)	address of test routine
0000227C	001F			1500+	DC	H' 31'	test number
0000227E	00			1501+	DC	X' 00'	
0000227F	00			1502+	DC	HL1' 00'	m field
00002280	E5D5D540 40404040			1503+	DC	CL8' VNN'	instruction name
00002288	000022F0			1504+	DC	A(RE31+16)	address of v2 source
0000228C	00002300			1505+	DC	A(RE31+32)	address of v3 source
00002290	00000010			1506+	DC	A(16)	result length
00002294	000022E0			1507+REA31	DC	A(RE31)	result address
00002298	00000000 00000000			1508+	DS	FD	gap
000022A0	00000000 00000000			1509+V1031	DS	XL16	V1 output
000022A8	00000000 00000000						
000022B0	00000000 00000000			1510+	DS	FD	gap
				1511+*			
000022B8				1512+X31	DS	OF	
000022B8	E310 5010 0014		00000010	1513+	LGF	R1, V2ADDR	load v2 source
000022BE	E761 0000 0806		00000000	1514+	VL	v22, 0(R1)	use v22 to test decoder
000022C4	E310 5014 0014		00000014	1515+	LGF	R1, V3ADDR	load v3 source
000022CA	E771 0000 0806		00000000	1516+	VL	v23, 0(R1)	use v23 to test decoder
000022D0	E766 7000 0E6E			1517+	VNN	V22, V22, V23	test instruction (dest is a source)
000022D6	E760 5028 080E		000022A0	1518+	VST	V22, V1031	save v1 output
000022DC	07FB			1519+	BR	R11	return
000022E0				1520+RE31	DC	OF	xl16 expected result
000022E0				1521+	DROP	R5	
000022E0	FFFFFFFF FFFFFFFF			1522	DC	XL16' FFFFFFFFFFFFFFFFFF FFFFFFFFFFFFFFFFFF'	result t
000022E8	FFFFFFFF FFFFFFFF						
000022F0	00000000 00000000			1523	DC	XL16' 0000000000000000 0000000000000000'	v2
000022F8	00000000 00000000						
00002300	00000000 00000000			1524	DC	XL16' 0000000000000000 0000000000000000'	v3
00002308	00000000 00000000						
				1525			
				1526	VRR_C	VNN	
00002310				1527+	DS	OFD	
00002310		00002310		1528+	USING	*, R5	base for test data and test routine
00002310	00002350			1529+T32	DC	A(X32)	address of test routine
00002314	0020			1530+	DC	H' 32'	test number
00002316	00			1531+	DC	X' 00'	
00002317	00			1532+	DC	HL1' 00'	m field
00002318	E5D5D540 40404040			1533+	DC	CL8' VNN'	instruction name
00002320	00002388			1534+	DC	A(RE32+16)	address of v2 source
00002324	00002398			1535+	DC	A(RE32+32)	address of v3 source
00002328	00000010			1536+	DC	A(16)	result length
0000232C	00002378			1537+REA32	DC	A(RE32)	result address
00002330	00000000 00000000			1538+	DS	FD	gap
00002338	00000000 00000000			1539+V1032	DS	XL16	V1 output
00002340	00000000 00000000						
00002348	00000000 00000000			1540+	DS	FD	gap
				1541+*			
00002350				1542+X32	DS	OF	
00002350	E310 5010 0014		00000010	1543+	LGF	R1, V2ADDR	load v2 source

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00002356	E761 0000 0806		00000000	1544+	VL	v22, 0(R1)	use v22 to test decoder
0000235C	E310 5014 0014		00000014	1545+	LGF	R1, V3ADDR	load v3 source
00002362	E771 0000 0806		00000000	1546+	VL	v23, 0(R1)	use v23 to test decoder
00002368	E766 7000 0E6E			1547+	VNN	V22, V22, V23	test instruction (dest is a source)
0000236E	E760 5028 080E		00002338	1548+	VST	V22, V1032	save v1 output
00002374	07FB			1549+	BR	R11	return
00002378				1550+RE32	DC	0F	xl16 expected result
00002378				1551+	DROP	R5	
00002378	00000000 00000000			1552	DC	XL16' 0000000000000000 0000000000000000'	result t
00002380	00000000 00000000						
00002388	FFFFFFFF FFFFFFFF			1553	DC	XL16' FFFFFFFFFFFFFFFFFF FFFFFFFFFFFFFFFFFF'	v2
00002390	FFFFFFFF FFFFFFFF						
00002398	FFFFFFFF FFFFFFFF			1554	DC	XL16' FFFFFFFFFFFFFFFFFF FFFFFFFFFFFFFFFFFF'	v3
000023A0	FFFFFFFF FFFFFFFF						
				1555			
000023A8				1556	VRR_C	VNN	
000023A8		000023A8		1557+	DS	0FD	
000023A8	000023E8			1558+	USING	*, R5	base for test data and test routine
000023AC	0021			1559+T33	DC	A(X33)	address of test routine
000023AE	00			1560+	DC	H' 33'	test number
000023AF	00			1561+	DC	X' 00'	
000023B0	E5D5D540 40404040			1562+	DC	HL1' 00'	m field
000023B8	00002420			1563+	DC	CL8' VNN'	instruction name
000023BC	00002430			1564+	DC	A(RE33+16)	address of v2 source
000023C0	00000010			1565+	DC	A(RE33+32)	address of v3 source
000023C4	00002410			1566+	DC	A(16)	result length
000023C8	00000000 00000000			1567+REA33	DC	A(RE33)	result address
000023D0	00000000 00000000			1568+	DS	FD	gap
000023D8	00000000 00000000			1569+V1033	DS	XL16	V1 output
000023E0	00000000 00000000			1570+	DS	FD	gap
				1571+*			
000023E8				1572+X33	DS	0F	
000023E8	E310 5010 0014		00000010	1573+	LGF	R1, V2ADDR	load v2 source
000023EE	E761 0000 0806		00000000	1574+	VL	v22, 0(R1)	use v22 to test decoder
000023F4	E310 5014 0014		00000014	1575+	LGF	R1, V3ADDR	load v3 source
000023FA	E771 0000 0806		00000000	1576+	VL	v23, 0(R1)	use v23 to test decoder
00002400	E766 7000 0E6E			1577+	VNN	V22, V22, V23	test instruction (dest is a source)
00002406	E760 5028 080E		000023D0	1578+	VST	V22, V1033	save v1 output
0000240C	07FB			1579+	BR	R11	return
00002410				1580+RE33	DC	0F	xl16 expected result
00002410				1581+	DROP	R5	
00002410	FFFEFD FC FBFAF9F8			1582	DC	XL16' FFFEFD FC FBFAF9F8 F7F6F5F4F3F2F1F0'	result t
00002418	F7F6F5F4 F3F2F1F0						
00002420	00010203 04050607			1583	DC	XL16' 0001020304050607 08090A0B0C0D0E0F'	v2
00002428	08090A0B 0C0D0E0F						
00002430	FFFFFFFF FFFFFFFF			1584	DC	XL16' FFFFFFFFFFFFFFFFFF FFFFFFFFFFFFFFFFFF'	v3
00002438	FFFFFFFF FFFFFFFF						
				1585			
00002440				1586	VRR_C	VNN	
00002440		00002440		1587+	DS	0FD	
00002440	00002480			1588+	USING	*, R5	base for test data and test routine
00002444	0022			1589+T34	DC	A(X34)	address of test routine
00002446	00			1590+	DC	H' 34'	test number
00002447	00			1591+	DC	X' 00'	
				1592+	DC	HL1' 00'	m field

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00002448	E5D5D540 40404040			1593+	DC	CL8' VNN'	instruction name
00002450	000024B8			1594+	DC	A(RE34+16)	address of v2 source
00002454	000024C8			1595+	DC	A(RE34+32)	address of v3 source
00002458	00000010			1596+	DC	A(16)	result length
0000245C	000024A8			1597+REA34	DC	A(RE34)	result address
00002460	00000000 00000000			1598+	DS	FD	gap
00002468	00000000 00000000			1599+V1034	DS	XL16	V1 output
00002470	00000000 00000000						
00002478	00000000 00000000			1600+	DS	FD	gap
				1601+*			
00002480				1602+X34	DS	OF	
00002480	E310 5010 0014		00000010	1603+	LGF	R1, V2ADDR	load v2 source
00002486	E761 0000 0806		00000000	1604+	VL	v22, 0(R1)	use v22 to test decoder
0000248C	E310 5014 0014		00000014	1605+	LGF	R1, V3ADDR	load v3 source
00002492	E771 0000 0806		00000000	1606+	VL	v23, 0(R1)	use v23 to test decoder
00002498	E766 7000 0E6E			1607+	VNN	V22, V22, V23	test instruction (dest is a source)
0000249E	E760 5028 080E		00002468	1608+	VST	V22, V1034	save v1 output
000024A4	07FB			1609+	BR	R11	return
000024A8				1610+RE34	DC	OF	xl16 expected result
000024A8				1611+	DROP	R5	
000024A8	0F1F2F3F 4F5F6F7F			1612	DC	XL16' 0F1F2F3F4F5F6F7F 8F9FAFBFCFDFEFFF'	result t
000024B0	8F9FAFBF CFDFEFFF						
000024B8	FFFFFFFF FFFFFFFF			1613	DC	XL16' FFFFFFFFFFFFFFFFFF FFFFFFFFFFFFFFFFFF'	v2
000024C0	FFFFFFFF FFFFFFFF						
000024C8	F0E0D0C0 B0A09080			1614	DC	XL16' F0E0D0C0B0A09080 7060504030201000'	v3
000024D0	70605040 30201000						
				1615			
000024D8				1616	VRR_C	VNN	
000024D8		000024D8		1617+	DS	OFD	
000024D8	00002518			1618+	USING	*, R5	base for test data and test routine
000024DC	0023			1619+T35	DC	A(X35)	address of test routine
000024DE	00			1620+	DC	H' 35'	test number
000024DF	00			1621+	DC	X' 00'	
000024E0	E5D5D540 40404040			1622+	DC	HL1' 00'	m field
000024E8	00002550			1623+	DC	CL8' VNN'	instruction name
000024EC	00002560			1624+	DC	A(RE35+16)	address of v2 source
000024F0	00000010			1625+	DC	A(RE35+32)	address of v3 source
000024F4	00002540			1626+	DC	A(16)	result length
000024F8	00000000 00000000			1627+REA35	DC	A(RE35)	result address
000024F8	00000000 00000000			1628+	DS	FD	gap
00002500	00000000 00000000			1629+V1035	DS	XL16	V1 output
00002508	00000000 00000000						
00002510	00000000 00000000			1630+	DS	FD	gap
				1631+*			
00002518				1632+X35	DS	OF	
00002518	E310 5010 0014		00000010	1633+	LGF	R1, V2ADDR	load v2 source
0000251E	E761 0000 0806		00000000	1634+	VL	v22, 0(R1)	use v22 to test decoder
00002524	E310 5014 0014		00000014	1635+	LGF	R1, V3ADDR	load v3 source
0000252A	E771 0000 0806		00000000	1636+	VL	v23, 0(R1)	use v23 to test decoder
00002530	E766 7000 0E6E			1637+	VNN	V22, V22, V23	test instruction (dest is a source)
00002536	E760 5028 080E		00002500	1638+	VST	V22, V1035	save v1 output
0000253C	07FB			1639+	BR	R11	return
00002540				1640+RE35	DC	OF	xl16 expected result
00002540				1641+	DROP	R5	
00002540	0F1F2FFF 4F5F6FFF			1642	DC	XL16' 0F1F2FFF4F5F6FFF 8F9FAFFF CFDFEFFF'	result t
00002548	8F9FAFFF CFDFEFFF						

LOC	OBJECT CODE	ADDR1	ADDR2	STMT				
00002550	FFFFFFF0 FFFFFFF0			1643	DC	XL16' FFFFFFF0FFFFFFF0 FFFFFFF0FFFFFFF'	v2	
00002558	FFFFFFF0 FFFFFFFF							
00002560	F0E0D0C0 B0A09080			1644	DC	XL16' F0E0D0C0B0A09080 7060504030201000'	v3	
00002568	70605040 30201000							
				1645				
				1646 *				
				1647 *	VOC	- Vector OR with Complement		
				1648 *				
				1649				
00002570				1650	VRR_C VOC			
00002570		00002570		1651+	DS	OFD		
00002570	000025B0			1652+	USING	*, R5	base for test data and test routine	
00002574	0024			1653+T36	DC	A(X36)	address of test routine	
00002576	00			1654+	DC	H' 36'	test number	
00002577	00			1655+	DC	X' 00'		
00002578	E5D6C340 40404040			1656+	DC	HL1' 00'	m field	
00002580	000025E8			1657+	DC	CL8' VOC'	instruction name	
00002584	000025F8			1658+	DC	A(RE36+16)	address of v2 source	
00002588	00000010			1659+	DC	A(RE36+32)	address of v3 source	
0000258C	000025D8			1660+	DC	A(16)	result length	
00002590	00000000 00000000			1661+REA36	DC	A(RE36)	result address	
00002598	00000000 00000000			1662+	DS	FD	gap	
000025A0	00000000 00000000			1663+V1036	DS	XL16	V1 output	
000025A8	00000000 00000000			1664+	DS	FD	gap	
				1665+*				
000025B0				1666+X36	DS	OF		
000025B0	E310 5010 0014		00000010	1667+	LGF	R1, V2ADDR	load v2 source	
000025B6	E761 0000 0806		00000000	1668+	VL	v22, 0(R1)	use v22 to test decoder	
000025BC	E310 5014 0014		00000014	1669+	LGF	R1, V3ADDR	load v3 source	
000025C2	E771 0000 0806		00000000	1670+	VL	v23, 0(R1)	use v23 to test decoder	
000025C8	E766 7000 0E6F			1671+	VOC	V22, V22, V23	test instruction (dest is a source)	
000025CE	E760 5028 080E		00002598	1672+	VST	V22, V1036	save v1 output	
000025D4	07FB			1673+	BR	R11	return	
000025D8				1674+RE36	DC	OF	xl16 expected result	
000025D8				1675+	DROP	R5		
000025D8	FFFFFFFF FFFFFFFF			1676	DC	XL16' FFFFFFFFFFFFFFFFFF FFFFFFFFFFFFFFFFFF'	result t	
000025E0	FFFFFFFF FFFFFFFF							
000025E8	00000000 00000000			1677	DC	XL16' 0000000000000000 0000000000000000'	v2	
000025F0	00000000 00000000							
000025F8	00000000 00000000			1678	DC	XL16' 0000000000000000 0000000000000000'	v3	
00002600	00000000 00000000							
				1679				
00002608				1680	VRR_C VOC			
00002608		00002608		1681+	DS	OFD		
00002608	00002648			1682+	USING	*, R5	base for test data and test routine	
0000260C	0025			1683+T37	DC	A(X37)	address of test routine	
0000260E	00			1684+	DC	H' 37'	test number	
0000260F	00			1685+	DC	X' 00'		
00002610	E5D6C340 40404040			1686+	DC	HL1' 00'	m field	
00002618	00002680			1687+	DC	CL8' VOC'	instruction name	
0000261C	00002690			1688+	DC	A(RE37+16)	address of v2 source	
00002620	00000010			1689+	DC	A(RE37+32)	address of v3 source	
00002624	00002670			1690+	DC	A(16)	result length	
00002628	00000000 00000000			1691+REA37	DC	A(RE37)	result address	
				1692+	DS	FD	gap	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00002630	00000000 00000000			1693+V1037	DS	XL16	V1 output
00002638	00000000 00000000						
00002640	00000000 00000000			1694+	DS	FD	gap
				1695+*			
00002648				1696+X37	DS	0F	
00002648	E310 5010 0014		00000010	1697+	LGF	R1, V2ADDR	load v2 source
0000264E	E761 0000 0806		00000000	1698+	VL	v22, 0(R1)	use v22 to test decoder
00002654	E310 5014 0014		00000014	1699+	LGF	R1, V3ADDR	load v3 source
0000265A	E771 0000 0806		00000000	1700+	VL	v23, 0(R1)	use v23 to test decoder
00002660	E766 7000 0E6F			1701+	VOC	V22, V22, V23	test instruction (dest is a source)
00002666	E760 5028 080E		00002630	1702+	VST	V22, V1037	save v1 output
0000266C	07FB			1703+	BR	R11	return
00002670				1704+RE37	DC	0F	xl16 expected result
00002670				1705+	DROP	R5	
00002670	FFFFFFFF FFFFFFFF			1706	DC	XL16' FFFFFFFFFFFFFFFFFF FFFFFFFFFFFFFFFFFF'	result t
00002678	FFFFFFFF FFFFFFFF						
00002680	FFFFFFFF FFFFFFFF			1707	DC	XL16' FFFFFFFFFFFFFFFFFF FFFFFFFFFFFFFFFFFF'	v2
00002688	FFFFFFFF FFFFFFFF						
00002690	FFFFFFFF FFFFFFFF			1708	DC	XL16' FFFFFFFFFFFFFFFFFF FFFFFFFFFFFFFFFFFF'	v3
00002698	FFFFFFFF FFFFFFFF						
				1709			
000026A0				1710	VRR_C VOC		
000026A0		000026A0		1711+	DS	0FD	
000026A0	000026E0			1712+	USING	*, R5	base for test data and test routine
000026A4	0026			1713+T38	DC	A(X38)	address of test routine
000026A6	00			1714+	DC	H' 38'	test number
000026A7	00			1715+	DC	X' 00'	
000026A8	E5D6C340 40404040			1716+	DC	HL1' 00'	m field
000026B0	00002718			1717+	DC	CL8' VOC'	instruction name
000026B4	00002728			1718+	DC	A(RE38+16)	address of v2 source
000026B8	00000010			1719+	DC	A(RE38+32)	address of v3 source
000026BC	00002708			1720+	DC	A(16)	result length
000026C0	00000000 00000000			1721+REA38	DC	A(RE38)	result address
000026C8	00000000 00000000			1722+	DS	FD	gap
000026D0	00000000 00000000			1723+V1038	DS	XL16	V1 output
000026D8	00000000 00000000			1724+	DS	FD	gap
				1725+*			
000026E0				1726+X38	DS	0F	
000026E0	E310 5010 0014		00000010	1727+	LGF	R1, V2ADDR	load v2 source
000026E6	E761 0000 0806		00000000	1728+	VL	v22, 0(R1)	use v22 to test decoder
000026EC	E310 5014 0014		00000014	1729+	LGF	R1, V3ADDR	load v3 source
000026F2	E771 0000 0806		00000000	1730+	VL	v23, 0(R1)	use v23 to test decoder
000026F8	E766 7000 0E6F			1731+	VOC	V22, V22, V23	test instruction (dest is a source)
000026FE	E760 5028 080E		000026C8	1732+	VST	V22, V1038	save v1 output
00002704	07FB			1733+	BR	R11	return
00002708				1734+RE38	DC	0F	xl16 expected result
00002708				1735+	DROP	R5	
00002708	00010203 04050607			1736	DC	XL16' 0001020304050607 08090A0B0C0D0E0F'	result t
00002710	08090A0B 0C0D0E0F						
00002718	00010203 04050607			1737	DC	XL16' 0001020304050607 08090A0B0C0D0E0F'	v2
00002720	08090A0B 0C0D0E0F						
00002728	FFFFFFFF FFFFFFFF			1738	DC	XL16' FFFFFFFFFFFFFFFFFF FFFFFFFFFFFFFFFFFF'	v3
00002730	FFFFFFFF FFFFFFFF						
				1739			
				1740	VRR_C VOC		

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00002738				1741+	DS	OFD	
00002738		00002738		1742+	USING	*, R5	base for test data and test routine
00002738	00002778			1743+T39	DC	A(X39)	address of test routine
0000273C	0027			1744+	DC	H' 39'	test number
0000273E	00			1745+	DC	X' 00'	
0000273F	00			1746+	DC	HL1' 00'	m field
00002740	E5D6C340 40404040			1747+	DC	CL8' VOC'	instruction name
00002748	000027B0			1748+	DC	A(RE39+16)	address of v2 source
0000274C	000027C0			1749+	DC	A(RE39+32)	address of v3 source
00002750	00000010			1750+	DC	A(16)	result length
00002754	000027A0			1751+REA39	DC	A(RE39)	result address
00002758	00000000 00000000			1752+	DS	FD	gap
00002760	00000000 00000000			1753+V1039	DS	XL16	V1 output
00002768	00000000 00000000						
00002770	00000000 00000000			1754+	DS	FD	gap
				1755+*			
00002778				1756+X39	DS	OF	
00002778	E310 5010 0014		00000010	1757+	LGF	R1, V2ADDR	load v2 source
0000277E	E761 0000 0806		00000000	1758+	VL	v22, 0(R1)	use v22 to test decoder
00002784	E310 5014 0014		00000014	1759+	LGF	R1, V3ADDR	load v3 source
0000278A	E771 0000 0806		00000000	1760+	VL	v23, 0(R1)	use v23 to test decoder
00002790	E766 7000 0E6F			1761+	VOC	V22, V22, V23	test instruction (dest is a source)
00002796	E760 5028 080E		00002760	1762+	VST	V22, V1039	save v1 output
0000279C	07FB			1763+	BR	R11	return
000027A0				1764+RE39	DC	OF	xl16 expected result
000027A0				1765+	DROP	R5	
000027A0	FFFFFFFF FFFFFFFF			1766	DC	XL16' FFFFFFFFFFFFFFFFFF FFFFFFFFFFFFFFFFFF'	result t
000027A8	FFFFFFFF FFFFFFFF						
000027B0	FFFFFFFF FFFFFFFF			1767	DC	XL16' FFFFFFFFFFFFFFFFFF FFFFFFFFFFFFFFFFFF'	v2
000027B8	FFFFFFFF FFFFFFFF						
000027C0	F0E0D0C0 B0A09080			1768	DC	XL16' F0E0D0C0B0A09080 7060504030201000'	v3
000027C8	70605040 30201000						
				1769			
000027D0				1770	VRR_C	VOC	
000027D0		000027D0		1771+	DS	OFD	
000027D0	00002810			1772+	USING	*, R5	base for test data and test routine
000027D0				1773+T40	DC	A(X40)	address of test routine
000027D4	0028			1774+	DC	H' 40'	test number
000027D6	00			1775+	DC	X' 00'	
000027D7	00			1776+	DC	HL1' 00'	m field
000027D8	E5D6C340 40404040			1777+	DC	CL8' VOC'	instruction name
000027E0	00002848			1778+	DC	A(RE40+16)	address of v2 source
000027E4	00002858			1779+	DC	A(RE40+32)	address of v3 source
000027E8	00000010			1780+	DC	A(16)	result length
000027EC	00002838			1781+REA40	DC	A(RE40)	result address
000027F0	00000000 00000000			1782+	DS	FD	gap
000027F8	00000000 00000000			1783+V1040	DS	XL16	V1 output
00002800	00000000 00000000						
00002808	00000000 00000000			1784+	DS	FD	gap
				1785+*			
00002810				1786+X40	DS	OF	
00002810	E310 5010 0014		00000010	1787+	LGF	R1, V2ADDR	load v2 source
00002816	E761 0000 0806		00000000	1788+	VL	v22, 0(R1)	use v22 to test decoder
0000281C	E310 5014 0014		00000014	1789+	LGF	R1, V3ADDR	load v3 source
00002822	E771 0000 0806		00000000	1790+	VL	v23, 0(R1)	use v23 to test decoder
00002828	E766 7000 0E6F			1791+	VOC	V22, V22, V23	test instruction (dest is a source)

LOC	OBJECT CODE	ADDR1	ADDR2	STMT				
0000282E	E760 5028 080E		000027F8	1792+	VST	V22, V1040	save v1 output	
00002834	07FB			1793+	BR	R11	return	
00002838				1794+RE40	DC	0F	xl16 expected result	
00002838				1795+	DROP	R5		
00002838	FFFFFF3F FFFFFFF7F			1796	DC	XL16' FFFFFFF3FFFFFFF7F FFFFFFFBFFFFFFF'	result	
00002840	FFFFFFBF FFFFFFFF							
00002848	FFFFFF00 FFFFFFF00			1797	DC	XL16' FFFFFFF00FFFFFF00 FFFFFFF00FFFFFFF'	v2	
00002850	FFFFFF00 FFFFFFFF							
00002858	F0E0D0C0 B0A09080			1798	DC	XL16' F0E0D0C0B0A09080 7060504030201000'	v3	
00002860	70605040 30201000							
				1799				
				1800				
00002868	00000000			1801	DC	F' 0'	END OF TABLE	
0000286C	00000000			1802	DC	F' 0'		
				1803 *				
				1804 *	table of pointers to individual load test			
				1805 *				
00002870				1806 E7TESTS	DS	0F		
				1807	PTTABLE			
00002870				1808+TTABLE	DS	0F		
00002870	000010A8			1809+	DC	A(T1)		
00002874	00001140			1810+	DC	A(T2)		
00002878	000011D8			1811+	DC	A(T3)		
0000287C	00001270			1812+	DC	A(T4)		
00002880	00001308			1813+	DC	A(T5)		
00002884	000013A0			1814+	DC	A(T6)		
00002888	00001438			1815+	DC	A(T7)		
0000288C	000014D0			1816+	DC	A(T8)		
00002890	00001568			1817+	DC	A(T9)		
00002894	00001600			1818+	DC	A(T10)		
00002898	00001698			1819+	DC	A(T11)		
0000289C	00001730			1820+	DC	A(T12)		
000028A0	000017C8			1821+	DC	A(T13)		
000028A4	00001860			1822+	DC	A(T14)		
000028A8	000018F8			1823+	DC	A(T15)		
000028AC	00001990			1824+	DC	A(T16)		
000028B0	00001A28			1825+	DC	A(T17)		
000028B4	00001AC0			1826+	DC	A(T18)		
000028B8	00001B58			1827+	DC	A(T19)		
000028BC	00001BF0			1828+	DC	A(T20)		
000028C0	00001C88			1829+	DC	A(T21)		
000028C4	00001D20			1830+	DC	A(T22)		
000028C8	00001DB8			1831+	DC	A(T23)		
000028CC	00001E50			1832+	DC	A(T24)		
000028D0	00001EE8			1833+	DC	A(T25)		
000028D4	00001F80			1834+	DC	A(T26)		
000028D8	00002018			1835+	DC	A(T27)		
000028DC	000020B0			1836+	DC	A(T28)		
000028E0	00002148			1837+	DC	A(T29)		
000028E4	000021E0			1838+	DC	A(T30)		
000028E8	00002278			1839+	DC	A(T31)		
000028EC	00002310			1840+	DC	A(T32)		
000028F0	000023A8			1841+	DC	A(T33)		
000028F4	00002440			1842+	DC	A(T34)		
000028F8	000024D8			1843+	DC	A(T35)		
000028FC	00002570			1844+	DC	A(T36)		

LOC	OBJECT	CODE	ADDR1	ADDR2	STMT	
					1856	*****
					1857	* Register equates
					1858	*****
		00000000	00000001	1860	R0	EQU 0
		00000001	00000001	1861	R1	EQU 1
		00000002	00000001	1862	R2	EQU 2
		00000003	00000001	1863	R3	EQU 3
		00000004	00000001	1864	R4	EQU 4
		00000005	00000001	1865	R5	EQU 5
		00000006	00000001	1866	R6	EQU 6
		00000007	00000001	1867	R7	EQU 7
		00000008	00000001	1868	R8	EQU 8
		00000009	00000001	1869	R9	EQU 9
		0000000A	00000001	1870	R10	EQU 10
		0000000B	00000001	1871	R11	EQU 11
		0000000C	00000001	1872	R12	EQU 12
		0000000D	00000001	1873	R13	EQU 13
		0000000E	00000001	1874	R14	EQU 14
		0000000F	00000001	1875	R15	EQU 15
					1877	*****
					1878	* Register equates
					1879	*****
		00000000	00000001	1881	V0	EQU 0
		00000001	00000001	1882	V1	EQU 1
		00000002	00000001	1883	V2	EQU 2
		00000003	00000001	1884	V3	EQU 3
		00000004	00000001	1885	V4	EQU 4
		00000005	00000001	1886	V5	EQU 5
		00000006	00000001	1887	V6	EQU 6
		00000007	00000001	1888	V7	EQU 7
		00000008	00000001	1889	V8	EQU 8
		00000009	00000001	1890	V9	EQU 9
		0000000A	00000001	1891	V10	EQU 10
		0000000B	00000001	1892	V11	EQU 11
		0000000C	00000001	1893	V12	EQU 12
		0000000D	00000001	1894	V13	EQU 13
		0000000E	00000001	1895	V14	EQU 14
		0000000F	00000001	1896	V15	EQU 15
		00000010	00000001	1897	V16	EQU 16
		00000011	00000001	1898	V17	EQU 17
		00000012	00000001	1899	V18	EQU 18
		00000013	00000001	1900	V19	EQU 19
		00000014	00000001	1901	V20	EQU 20
		00000015	00000001	1902	V21	EQU 21

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES		
RE8	F	00001538	4	810	794	795	797
RE9	F	000015D0	4	840	824	825	827
REA1	A	000010C4	4	583			
REA10	A	0000161C	4	857			
REA11	A	000016B4	4	891			
REA12	A	0000174C	4	921			
REA13	A	000017E4	4	951			
REA14	A	0000187C	4	981			
REA15	A	00001914	4	1011			
REA16	A	000019AC	4	1045			
REA17	A	00001A44	4	1075			
REA18	A	00001ADC	4	1105			
REA19	A	00001B74	4	1135			
REA2	A	0000115C	4	613			
REA20	A	00001C0C	4	1165			
REA21	A	00001CA4	4	1199			
REA22	A	00001D3C	4	1229			
REA23	A	00001DD4	4	1259			
REA24	A	00001E6C	4	1289			
REA25	A	00001F04	4	1319			
REA26	A	00001F9C	4	1353			
REA27	A	00002034	4	1383			
REA28	A	000020CC	4	1413			
REA29	A	00002164	4	1443			
REA3	A	000011F4	4	643			
REA30	A	000021FC	4	1473			
REA31	A	00002294	4	1507			
REA32	A	0000232C	4	1537			
REA33	A	000023C4	4	1567			
REA34	A	0000245C	4	1597			
REA35	A	000024F4	4	1627			
REA36	A	0000258C	4	1661			
REA37	A	00002624	4	1691			
REA38	A	000026BC	4	1721			
REA39	A	00002754	4	1751			
REA4	A	0000128C	4	673			
REA40	A	000027EC	4	1781			
REA5	A	00001324	4	703			
REA6	A	000013BC	4	737			
REA7	A	00001454	4	767			
REA8	A	000014EC	4	797			
REA9	A	00001584	4	827			
READDR	A	0000001C	4	464	271		
REG2LOW	U	000000DD	1	410			
REG2PATT	U	AABBCCDD	1	409			
RELEN	A	00000018	4	463			
RPTDWSAV	D	00000430	8	335	322	326	
RPTERROR	I	000003DC	4	309	284		
RPTSAVE	F	00000424	4	332	309	329	
RPTSVR5	F	00000428	4	333	310	328	
SKL0001	U	0000004E	1	193	209		
SKL0002	U	00000050	1	229	245		
SKT0001	C	0000022A	20	190	193	210	
SKT0002	C	000002D4	20	226	229	246	
SVOLDPSW	U	00000140	0	129			
T1	A	000010A8	4	575	1809		

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES	
T10	A	00001600	4	849	1818	
T11	A	00001698	4	883	1819	
T12	A	00001730	4	913	1820	
T13	A	000017C8	4	943	1821	
T14	A	00001860	4	973	1822	
T15	A	000018F8	4	1003	1823	
T16	A	00001990	4	1037	1824	
T17	A	00001A28	4	1067	1825	
T18	A	00001AC0	4	1097	1826	
T19	A	00001B58	4	1127	1827	
T2	A	00001140	4	605	1810	
T20	A	00001BF0	4	1157	1828	
T21	A	00001C88	4	1191	1829	
T22	A	00001D20	4	1221	1830	
T23	A	00001DB8	4	1251	1831	
T24	A	00001E50	4	1281	1832	
T25	A	00001EE8	4	1311	1833	
T26	A	00001F80	4	1345	1834	
T27	A	00002018	4	1375	1835	
T28	A	000020B0	4	1405	1836	
T29	A	00002148	4	1435	1837	
T3	A	000011D8	4	635	1811	
T30	A	000021E0	4	1465	1838	
T31	A	00002278	4	1499	1839	
T32	A	00002310	4	1529	1840	
T33	A	000023A8	4	1559	1841	
T34	A	00002440	4	1589	1842	
T35	A	000024D8	4	1619	1843	
T36	A	00002570	4	1653	1844	
T37	A	00002608	4	1683	1845	
T38	A	000026A0	4	1713	1846	
T39	A	00002738	4	1743	1847	
T4	A	00001270	4	665	1812	
T40	A	000027D0	4	1773	1848	
T5	A	00001308	4	695	1813	
T6	A	000013A0	4	729	1814	
T7	A	00001438	4	759	1815	
T8	A	000014D0	4	789	1816	
T9	A	00001568	4	819	1817	
TESTING	F	00001004	4	421	265	
TNUM	H	00000004	2	456	264	312
TSUB	A	00000000	4	455	268	
TTABLE	F	00002870	4	1808		
V0	U	00000000	1	1881		
V1	U	00000001	1	1882	267	
V10	U	0000000A	1	1891		
V11	U	0000000B	1	1892		
V12	U	0000000C	1	1893		
V13	U	0000000D	1	1894		
V14	U	0000000E	1	1895		
V15	U	0000000F	1	1896		
V16	U	00000010	1	1897		
V17	U	00000011	1	1898		
V18	U	00000012	1	1899		
V19	U	00000013	1	1900		
V1FUDGE	X	00001088	16	447	267	

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES												
V101	X	000010D0	16	585	594												
V1010	X	00001628	16	859	868												
V1011	X	000016C0	16	893	902												
V1012	X	00001758	16	923	932												
V1013	X	000017F0	16	953	962												
V1014	X	00001888	16	983	992												
V1015	X	00001920	16	1013	1022												
V1016	X	000019B8	16	1047	1056												
V1017	X	00001A50	16	1077	1086												
V1018	X	00001AE8	16	1107	1116												
V1019	X	00001B80	16	1137	1146												
V102	X	00001168	16	615	624												
V1020	X	00001C18	16	1167	1176												
V1021	X	00001CB0	16	1201	1210												
V1022	X	00001D48	16	1231	1240												
V1023	X	00001DE0	16	1261	1270												
V1024	X	00001E78	16	1291	1300												
V1025	X	00001F10	16	1321	1330												
V1026	X	00001FA8	16	1355	1364												
V1027	X	00002040	16	1385	1394												
V1028	X	000020D8	16	1415	1424												
V1029	X	00002170	16	1445	1454												
V103	X	00001200	16	645	654												
V1030	X	00002208	16	1475	1484												
V1031	X	000022A0	16	1509	1518												
V1032	X	00002338	16	1539	1548												
V1033	X	000023D0	16	1569	1578												
V1034	X	00002468	16	1599	1608												
V1035	X	00002500	16	1629	1638												
V1036	X	00002598	16	1663	1672												
V1037	X	00002630	16	1693	1702												
V1038	X	000026C8	16	1723	1732												
V1039	X	00002760	16	1753	1762												
V104	X	00001298	16	675	684												
V1040	X	000027F8	16	1783	1792												
V105	X	00001330	16	705	714												
V106	X	000013C8	16	739	748												
V107	X	00001460	16	769	778												
V108	X	000014F8	16	799	808												
V109	X	00001590	16	829	838												
V10UTPUT	X	00000028	16	466	272												
V2	U	00000002	1	1883													
V20	U	00000014	1	1901													
V21	U	00000015	1	1902													
V22	U	00000016	1	1903	590	593	594	620	623	624	650	653	654	680	683	684	710
					713	714	744	747	748	774	777	778	804	807	808	834	837
					838	864	867	868	898	901	902	928	931	932	958	961	962
					988	991	992	1018	1021	1022	1052	1055	1056	1082	1085	1086	1112
					1115	1116	1142	1145	1146	1172	1175	1176	1206	1209	1210	1236	1239
					1240	1266	1269	1270	1296	1299	1300	1326	1329	1330	1360	1363	1364
					1390	1393	1394	1420	1423	1424	1450	1453	1454	1480	1483	1484	1514
					1517	1518	1544	1547	1548	1574	1577	1578	1604	1607	1608	1634	1637
					1638	1668	1671	1672	1698	1701	1702	1728	1731	1732	1758	1761	1762
					1788	1791	1792										
V23	U	00000017	1	1904	592	593	622	623	652	653	682	683	712	713	746	747	776
					777	806	807	836	837	866	867	900	901	930	931	960	961

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES					
X33	F	000023E8	4	1572	1559					
X34	F	00002480	4	1602	1589					
X35	F	00002518	4	1632	1619					
X36	F	000025B0	4	1666	1653					
X37	F	00002648	4	1696	1683					
X38	F	000026E0	4	1726	1713					
X39	F	00002778	4	1756	1743					
X4	F	000012B0	4	678	665					
X40	F	00002810	4	1786	1773					
X5	F	00001348	4	708	695					
X6	F	000013E0	4	742	729					
X7	F	00001478	4	772	759					
X8	F	00001510	4	802	789					
X9	F	000015A8	4	832	819					
XC0001	U	000002D0	1	213	205					
XC0002	U	00000380	1	249	241					
ZVE7TST	J	00000000	10528	126	129	131	135	139	419	127
=A(E7TESTS)	A	00000534	4	398	255					
=AL2(L' MSGMSG)	R	0000053A	2	400	347					
=F' 1'	F	00000530	4	397	240	290				
=F' 64'	F	0000052C	4	396	204					
=H' 0'	H	00000538	2	399	342					

DESC	SYMBOL	SIZE	POS	ADDR
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Entry: 0

Image	IMAGE	10528	0000- 291F	0000- 291F
Regi on		10528	0000- 291F	0000- 291F
CSECT	ZVE7TST	10528	0000- 291F	0000- 291F

STMT	FILE NAME
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1	/home/tn529/sharedvfp/tests/zvector-e7-11-logical.asm
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**** NO ERRORS FOUND ****